

TIMING AND CONGESTION DRIVEN ALGORITHMS FOR FPGA PLACEMENT

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Placement is one of the most important steps in physical design for VLSI circuits. For field programmable gate arrays (FPGAs), the placement step determines the location of each logic block. I present novel timing and congestion driven placement algorithms for FPGAs with minimal runtime overhead. By predicting the post-routing timing-critical edges and estimating congestion accurately, this algorithm is able to simultaneously reduce the critical path delay and the minimum number of routing tracks. The core of the algorithm consists of a criticality-history record of connection edges and a congestion map. This approach is applied to the 20 largest Microelectronics Center of North Carolina (MCNC) benchmark circuits. Experimental results show that compared with the state-of-the-art FPGA place and route package, the Versatile Place and Route (VPR) suite, this algorithm yields an average of 8.1% reduction (maximum 30.5%) in the critical path delay and 5% reduction in channel width. Meanwhile, the average runtime of the algorithm is only 2.3X as of VPR.

## ACKNOWLEDGMENTS

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## CHAPTER 1

### INTRODUCTION

#### 1.1. Motivation

Field programmable gate arrays (FPGAs) have gained rapid commercial acceptance as their user-programmability offers fast manufacturing turnaround and low non-recurring engineering (NRE) cost. However, the speed and area efficiency of FPGAs lag behind the application specific integrated circuits (ASICs) and hence deserve more research efforts for optimizations. Our motivation is to improve the performance and reduce the occupied area of an FPGA by improving the placement algorithm in the process of physical design.

##### 1.1.1. *The Surge of FPGAs*

The FPGA industry has grown to multi-billion market today. Table 1.1 shows the revenue of 4 industry leaders in manufacturing FPGAs.

FPGAs are being widely used in a wide range of applications, ranging from simple glue logic in a lot of low-cost products, to building up development platforms for many large-scale designs. Applications of FPGAs include digital signal processing, networking, storage systems, aerospace and defense systems, ASIC prototyping, medical imaging, computer vision,

Table 1.1: Total revenue of industry players (Unit: million\$) [18].

	1Q03	2Q03	3Q03	4Q03	1Q04	2Q04
Xilinx	306	313	316	366	403	424
Altera	195	205	209	217	242	268
Lattice	57	56	43	53	59	61
Actel	34	37	38	40	42	44
Total	592	611	606	676	746	797

speech recognition, cryptography, bioinformatics, computer hardware emulation, and so on. Originally, FPGAs began as competitors to complex programmable logic devices (CPLDs) which are used as glue logic for printed circuit boards (PCBs).

Although prices of FPGA products vary, they are considerably lower than the investment in a fully customized solution. FPGAs are used in a similar way to customer-specific, standard cell designs, most commonly used in meeting multiple system design requirements and/or applications via the use of a single device, with its main advantage being its reconfigurability and short development cycles. The FPGA market is forecast to grow from \$1,895.0 million in 2005 to \$2,756.7 million by 2010 [6].

#### 1.1.2. *The Advantages of FPGAs*

FPGAs have several advantages such as a shorter time to market, capability of being re-programmed in the field to improve performance or fix bugs, and lower non-recurring engineering costs.

Time to market is crucial to the success of a commercial product. Figure 1.1 shows the difference of profitability between an early product and a late product. In the industrial market, designers have a significant incentive to get their products to market quickly to maximize revenue and time-in-market. By utilizing the reprogrammability of FPGAs, electronic device vendors can ship full-reconfigurable designs first. After that, vendors may launch cheaper, less flexible versions of their FPGAs while keep updating the committed designs. The development of these designs is made on regular FPGAs and then migrated into a fixed version that more resembles an ASIC.

NRE cost refers to the one-time cost of researching, designing, and testing a new product before producing it in a high unit volume. When budgeting for a project, NRE must be considered in order to analyze if a new product will be profitable. Even though a company will pay for NRE on a project only once, NRE can be considerably high and the product will have to sell well enough to compensate for the initial investment. With the mask costs approaching a one million dollar price tag, and NRE costs in the neighborhood of another

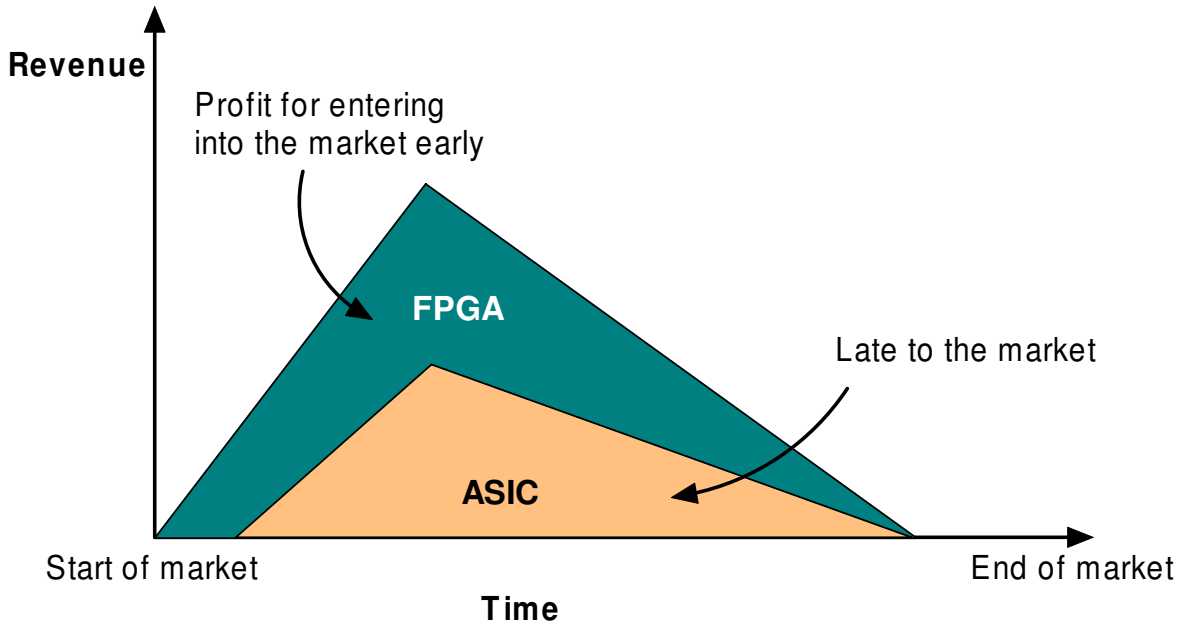


Figure 1.1: Time to market is critical.

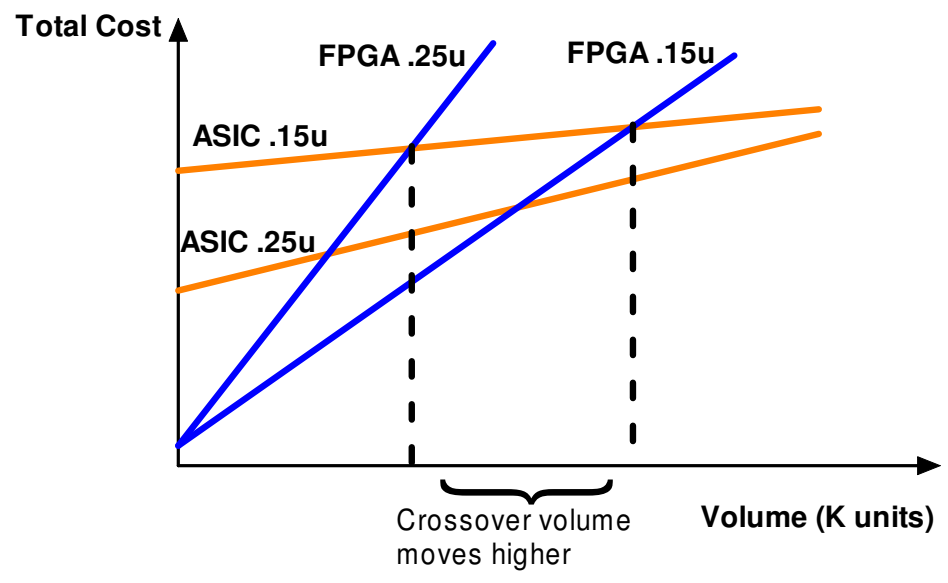


Figure 1.2: Production cost.

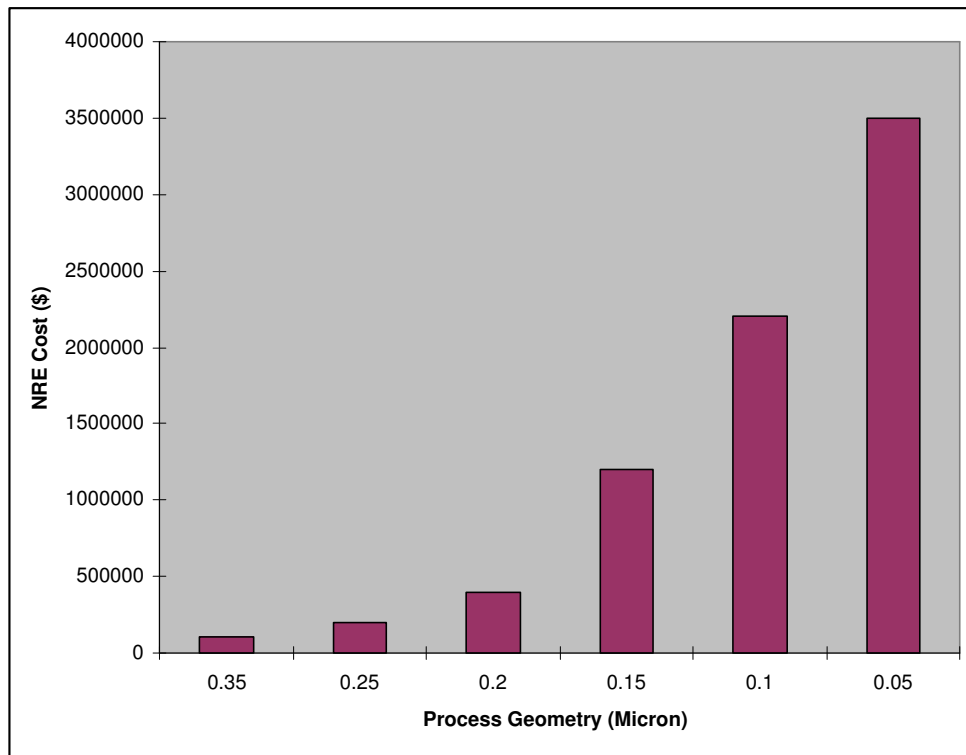


Figure 1.3: The exploding NRE cost of ASICs.

million dollars, it is very difficult to justify an ASIC for a low unit volume. Figure 1.3 shows the exponentially growing of NRE cost for ASICs. FPGAs, on the other hand, have improved their capacity to build systems on a chip with more than million ASIC equivalent gates and a few megabits of on chip RAM. FPGAs are becoming even more attractive when the process geometry scales below 90nm. It is shown from Figure 1.2 that the profitable volume of a FPGA design grows as the technology scales down.

A recent trend has been to take the coarse-grained architectural approach a step further by combining the logic blocks and interconnects of traditional FPGAs with embedded microprocessors and related peripherals to form a complete “system on a programmable chip”. Examples of such hybrid technologies can be found in the Xilinx Virtex<sup>TM</sup>-4 devices [30], which include one or more Xilinx’s PowerPC<sup>TM</sup> processors embedded within the

FPGA’s logic fabric. The Atmel’s field programmable system level integrated circuits (FPGA) device is another example, which uses Atmel’s AVR® processor in combination with Atmel’s programmable logic architecture [23]. An alternate approach is to use soft processor cores that are implemented within the FPGA logic. These cores include the Xilinx MicroBlaze™ [28] and PicoBlaze™ [29], the Altera Nios® II processors [21], and the open source LatticeMico8™ [14], as well as third-party (either commercial or free) processor cores. many modern FPGAs have the ability to be reprogrammed at “run time”, and this is leading to the idea of reconfigurable computing or reconfigurable systems – CPUs that reconfigure themselves to suit the task at hand [59]. Current FPGA tools, however, still can not fully support this methodology.

### 1.1.3. *The Disadvantages of FPGAs*

FPGAs are generally slower than their application-specific integrated circuit (ASIC) counterparts, can’t handle as complex a design, and draw more power.

The work in [38] presented empirical measurements quantifying the gap between FPGAs and ASICs. It is observed that for circuits implemented entirely using look-up tables (LUTs) and flip-flops (logic-only), an FPGA is on average 40 times larger and 3.2 times slower than a standard cell implementation.

Table 1.2 summarizes the comparison between FPGAs and ASICs.

## 1.2. Research Goals and Platform

As FPGAs become more and more popular and important, it is more urgent to improve their performance as well as area efficiency than ever before.

My research goal is to improve timing and reduce routing tracks given an FPGA design. The complete computer aided design (CAD) flow for synthesizing a FPGA based design consists of logic synthesis, mapping, placement and routing. My work focuses on placement algorithms. The objectives of my work are:

- (i) To study the current placement algorithms and come up with a novel approach which is capable of improve the performance of a FPGA design.

Table 1.2: Comparisons between FPGAs and ASICs.

	FPGA	Standard Cell ASIC
NRE	Low	High
Unit Cost	High	Low
Risk	Low	High
Development Span	Short	Long
<b>Performance</b>	<b>Low</b>	<b>High</b>
<b>Area</b>	<b>Large</b>	<b>Small</b>
Capacity	Low	High
Power	High	Low

- (ii) To research the current placement algorithms and create a novel approach which is capable of reduce the area of a FPGA design.
- (iii) To implement these two algorithms and integrate them into the popular Versatile Place and Route (VPR) [4] CAD suite.
- (iv) To minimize the runtime overhead of these two algorithms so that they can be integrated in any commercial and practical placement algorithm.

I take VPR as the platform to integrate and evaluate my algorithms because it is considered as the state-of-the-art academic system to explore placement, routing and architecture for FPGAs. Also its source code is open.

### 1.3. Thesis Organization

This thesis is organized as follows. Chapter 2 provides an overview of FPGA architectures and the CAD flow for logic synthesis. It also reviews previous works on timing and routability optimization. Chapter 3 describes the framework of VPR, the file format of its input and output, the core of its placement algorithm. Chapter 4 proposes my congestion driven optimization. Chapter 5 proposes my timing driven optimization. Chapter 6 describes my

approach to minimize runtime. Experimental results are analyzed in chapter 4, 5 and 6. Chapter 7 draws the conclusion and discuss future research directions.

## CHAPTER 2

### BACKGROUND OF FPGA AND THE CAD FLOW

#### 2.1. FPGA Architecture

##### 2.1.1. *Overview*

A field programmable gate array (FPGA) is an electrical device containing programmable logic blocks, I/O pads, and programmable interconnects. The programmable logic blocks can be programmed to provide the functionality of basic logic gates such as AND, OR, XOR, NOT or more complex combinational functions such as multiplexers or simple math functions. The logic blocks also consist of flip flops which are used to build sequential circuits. The programmable routing implements the interconnections among logic blocks. Figure 2.1 shows a global view of a generic FPGA.

FPGAs originated from the complex programmable logic devices (CPLDs) of the early to mid 1980s. CPLDs and FPGAs include a relatively large number of programmable logic elements. CPLD logic gate densities range from the equivalent of several thousand to tens of thousands of logic gates, while FPGAs typically range from tens of thousands to several million.

The primary differences between CPLDs and FPGAs are architectural. A CPLD has a somewhat restrictive structure consisting of one or more programmable sum-of-products logic arrays feeding a relatively small number of clocked registers. The result of this is less flexibility, with the advantage of more predictable timing delays and a higher logic-to-interconnect ratio. The FPGA architectures, on the other hand, are dominated by interconnect. This makes them far more flexible (in terms of the range of designs that are practical for implementation within them) but also far more complex to design for.



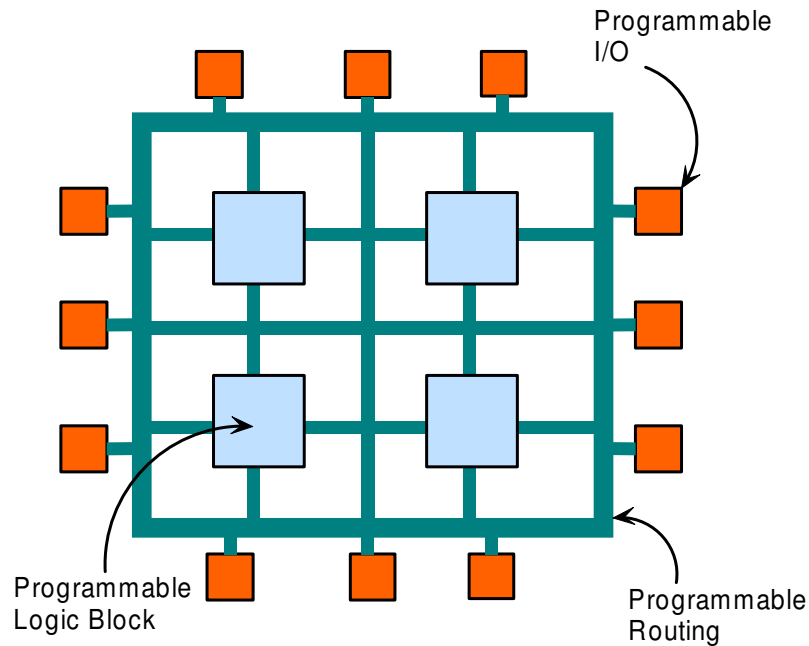


Figure 2.1: Overview of FPGA.

Another notable difference between CPLDs and FPGAs is the presence in most FPGAs of higher-level embedded functions (such as adders and multipliers) and embedded memories. A related, important difference is that many modern FPGAs support full or partial in-system reconfiguration, allowing their designs to be changed “on the fly” either for system upgrades or for dynamic reconfiguration as a normal part of system operation. Some FPGAs have the capability of partial re-configuration that lets one portion of the device be re-programmed while other portions continue running.

There are three different approaches to program an FPGA. The most widely used technology is using static random access memory (SRAM) cells to control pass transistors, multiplexers and tri-state buffers in order to configure the programmable routing and logic blocks. Figure 2.2 shows these SRAM-based switches. Usually, pass transistors use n-type metal-oxide-semiconductor field effect transistors (nMOS), rather than complementary transmission gates to get higher speed [10, 34]. Most commercial FPGAs, like most Xilinx FPGAs [27], the larger Altera devices [20] are SRAM-based. Another popular programming

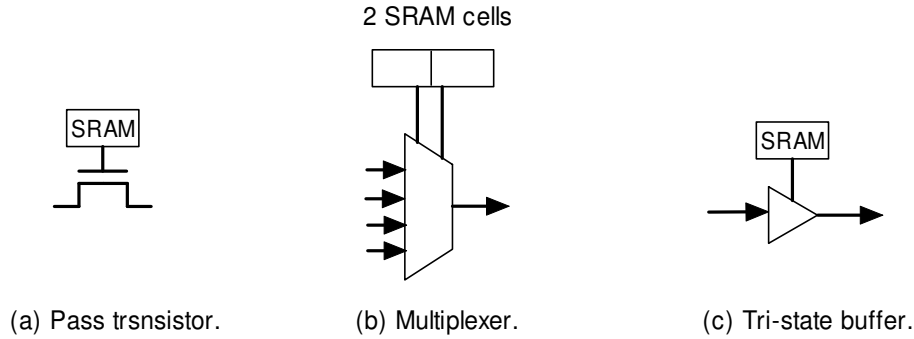


Figure 2.2: Three types of programming techniques used in SRAM-based FPGAs.

technology is antifuse which consumes less power than SRAM. But it can be programmed only once. Antifuse technology is used in Actel FPGAs [12].

### 2.1.2. Different FPGA Architectures

There are four widely used architectures for commercial FPGAs. Xilinx [26] and Lument [55] use *island-style*, Actel's FPGAs [13] are *row-based*, Altera's FPGAs [22] are *hierarchical*, while Algotronix uses *sea-of-gates* [31]. Figure 2.3 shows these four architectures. It should be noted here that new, non-FPGA architectures are beginning to emerge. Software-configurable microprocessors such as the Stretch® S5000 [25] adopt a hybrid approach by providing an array of processor cores and FPGA-like programmable cores on the same chip. Other devices, such as Mathstar's Field Programmable Object Array, or FPOA™ [24], provide arrays of higher-level programmable objects that lie somewhere between an FPGA's logic block and a more complex processor.

In this thesis, we focus on the most popular island-style FPGAs. Typically, an island-style FPGA consists of a two-dimensional array of configurable logic blocks (CLBs), vertical and horizontal routing channels, and input/output blocks. Figure 2.4 illustrates the top level architecture of an island-style FPGA. The configurable logic blocks, denoted as *CLB* in Figure 2.4, are customizable to implement the logic functions. The *connection block* [32], denoted as *C* in Figure 2.4, connects the CLB pins to the routing channels. A horizontal

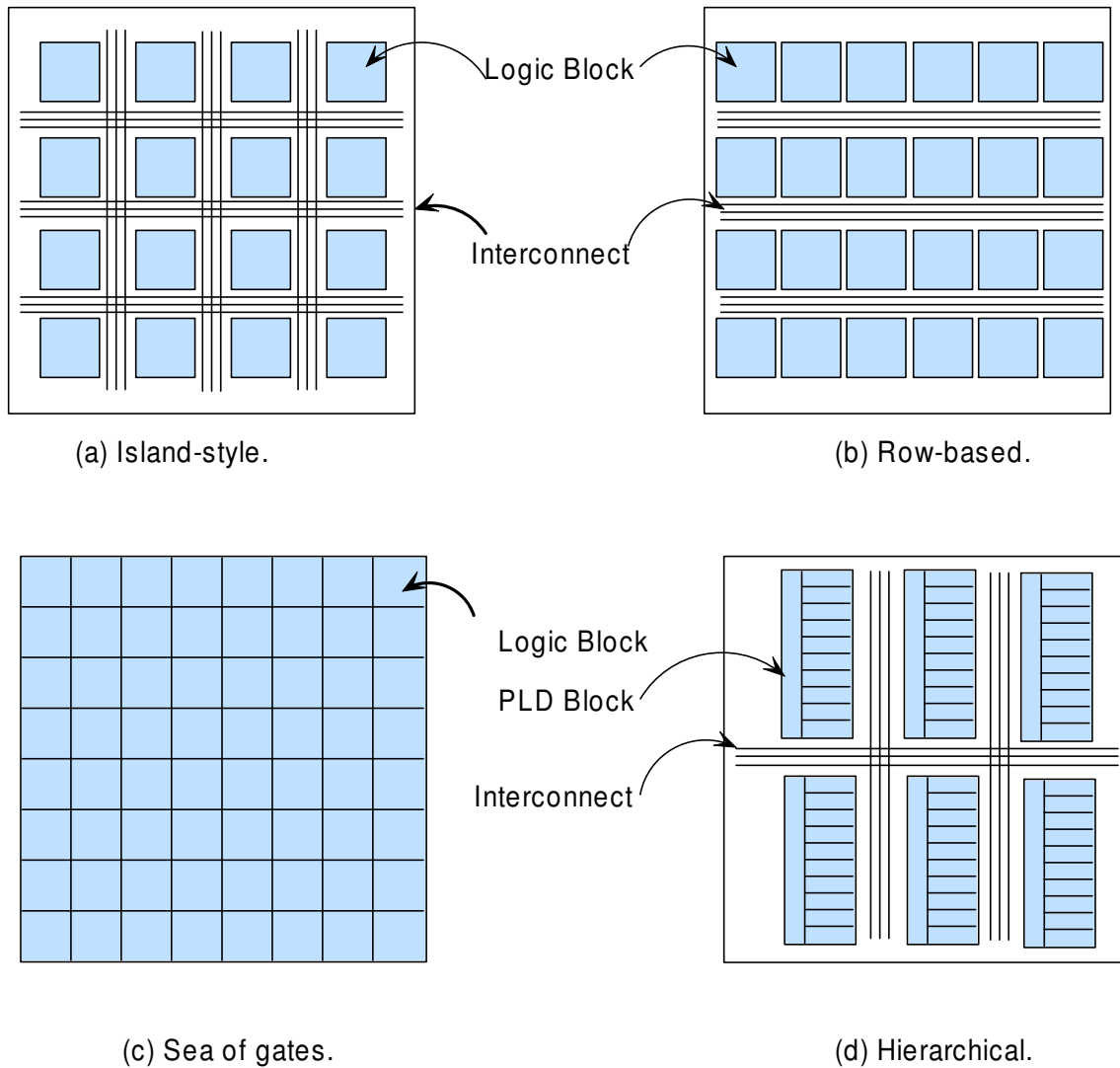


Figure 2.3: Different FPGA architectures.

routing channel and a vertical routing channel are connected via a *switch block* [32] denoted as  $S$  in Figure 2.4. A switch block contains a number of programmable switches which account for the connections of FPGA routing. Typically, the switches have higher resistance and capacitance, and hence result in significant delays. The routing channels are segmented in order to balance the circuit performance and routability. Routing tracks consist of a set of wires with different lengths where longer wires are desirable for timing-critical nets and shorter wires are intended for short connections to save routing resources. When routing is

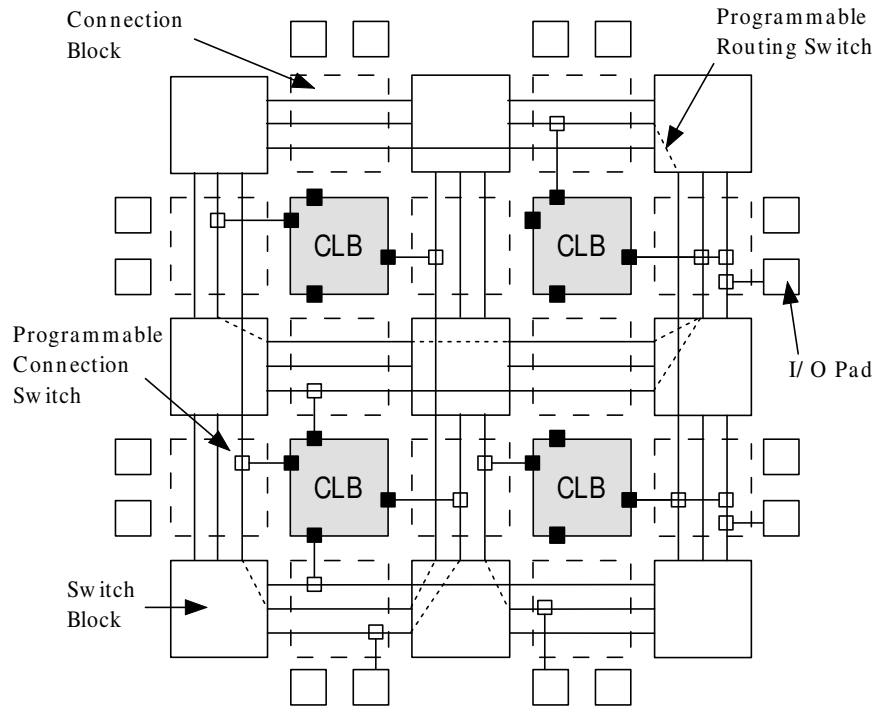


Figure 2.4: The architecture of an island-style FPGA.

completed for a given circuit, wires, connection blocks and switches will connect the pins of CLBs and input/output pads together. Each connection consists of a source pin and one or multiple sink pins and is called a net. As a result, the reduction of routing tracks will lead to smaller area.

### 2.1.3. Logic Block

In most FPGAs, the programmable logic blocks consist of clusters of look-up tables (LUTs) and flip flops along with local routing to connect the LUTs within a cluster. Figure 2.5 shows an example of a typical logic block. For an FPGA using cluster-based logic blocks, there are many local connections within a cluster. Since this local interconnect is faster than the general-purpose interconnect among logic blocks, cluster-based logic blocks can improve FPGA speed. Also, for an FPGA in which every logic block contains multiple LUTs, it will need fewer logic blocks to implement a circuit. On the other hand, if each logic block in

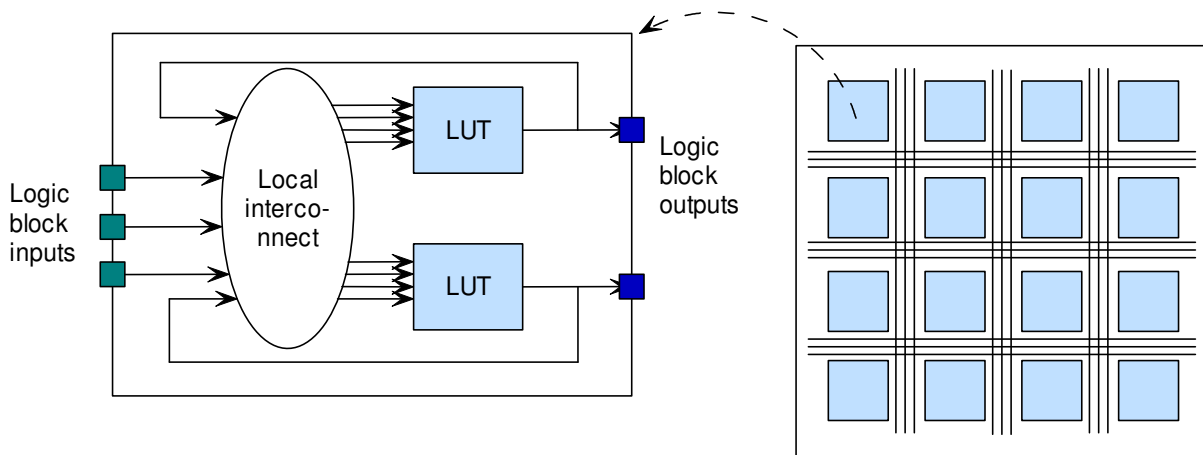


Figure 2.5: A logic block example containing two LUTs.

an FPGA contains only a single LUT, it will need much more logic blocks. This reduces the size of the placement and routing problem considerably. Since placement and routing is usually the most time-consuming step in mapping a design to an FPGA, cluster-based logic blocks can significantly reduce design compile time. As FPGAs grow larger, it is important to keep the compile time from growing too long. Otherwise, the key advantages of FPGAs, such as rapid prototyping and quick design turns, will be lost.

#### 2.1.4. Routing Fabric

The system of programmable interconnects allows the logic blocks of an FPGA to be interconnected as needed. These logic blocks and interconnects can be programmed after the manufacturing process by the customer/designer (hence “field programmable”) so that the FPGA can perform whatever logical function needed and can be reprogrammed anytime.

Routing can be divided into global routing and detailed routing. The global routing architecture of an FPGA specifies the relative width of the various wiring channels at different portions of the chip. For example, some FPGAs have a wider channel width near the center than near the borders. Some FPGAs use a uniform global routing, i.e., their channels near the center are as wide as the channels near the edges. In FPGAs, however, all routing

resources are prefabricated, so the width of all the routing channels is set by the FPGA manufacturer.

The detailed routing architecture of an FPGA defines how logic blocks inputs and outputs can be connected to routing tracks, and how routing tracks can be linked to each other.. Detailed routing architecture is the key element of an FPGA because:

- 1) Most of an FPGA's area is devoted to routing resources.
- 2) Interconnect routing delay assumes the major proportion of the total circuit delay.
- 3) Interconnect delay does not scale as well as logic delay with process shrinks, so the fraction of delay due to routing in FPGAs is increasing with each process generation.

The detailed routing architecture should consider the following issues:

- Which routing wires in the channel adjacent to a logic block input or output can connect to that logic block pin.
- Where each routing wire starts and how many logic blocks it spans.
- Where routing switches are located and which routing wires they can connect.
- Whether to use a pass transistor or a tri-state buffer for a routing switch.
- The size of the transistors used o build the various switches.
- The metal width and spacing of the various routing wires.

## 2.2. Design Steps with FPGAs

Implementing a circuit on an FPGA requires programming millions of programmable switches to their correct states. It is impossible for a developer to specify the state of each switch manually. In fact, a developer provides a description of a circuit in a hardware description language; i.e., VHSIC Hardware Description Language (VHDL) or Verilog. Computer-Aided Design (CAD) tools convert this high-level description into a bit-stream file which is used to configure an FPGA. The entire CAD flow is divided into a set of steps, as shown in Figure 2.6.

The first step is to synthesize the VHDL description into a netlist of basic gates and clock signals. This step is technology-independent.

Then, the second step optimizes this netlist and maps it to the target FPGA device. This step is further illustrated in Figure 2.7. First, technology-independent logic optimization is performed. After that, this netlist of basic gates are mapped onto LUTs and packed into the logic blocks of a specific FPGA device.

The third step is placement. Placement determines the location of each logic block, i.e., it decides the coordinate of each logic block. The optimization objectives include minimizing wirelength, maximizing circuit speed and so on. This phase is also shown in Figure 2.7.

Once locations of all the logic blocks in a circuit have been fixed, a router is started to connect all pins in the same net together. A bit-stream used to program all the switches is produced in this phase. This is the final step in physical design.

A hardware designer may perform a lot of simulations and tests in this flow. Functional simulation is done on the level of VHDL description. After placement and routing, precise timing information is acquired. At this point, timing verification can be completed. Finally, we can download the bit-stream to program the FPGA device and test it in-field.

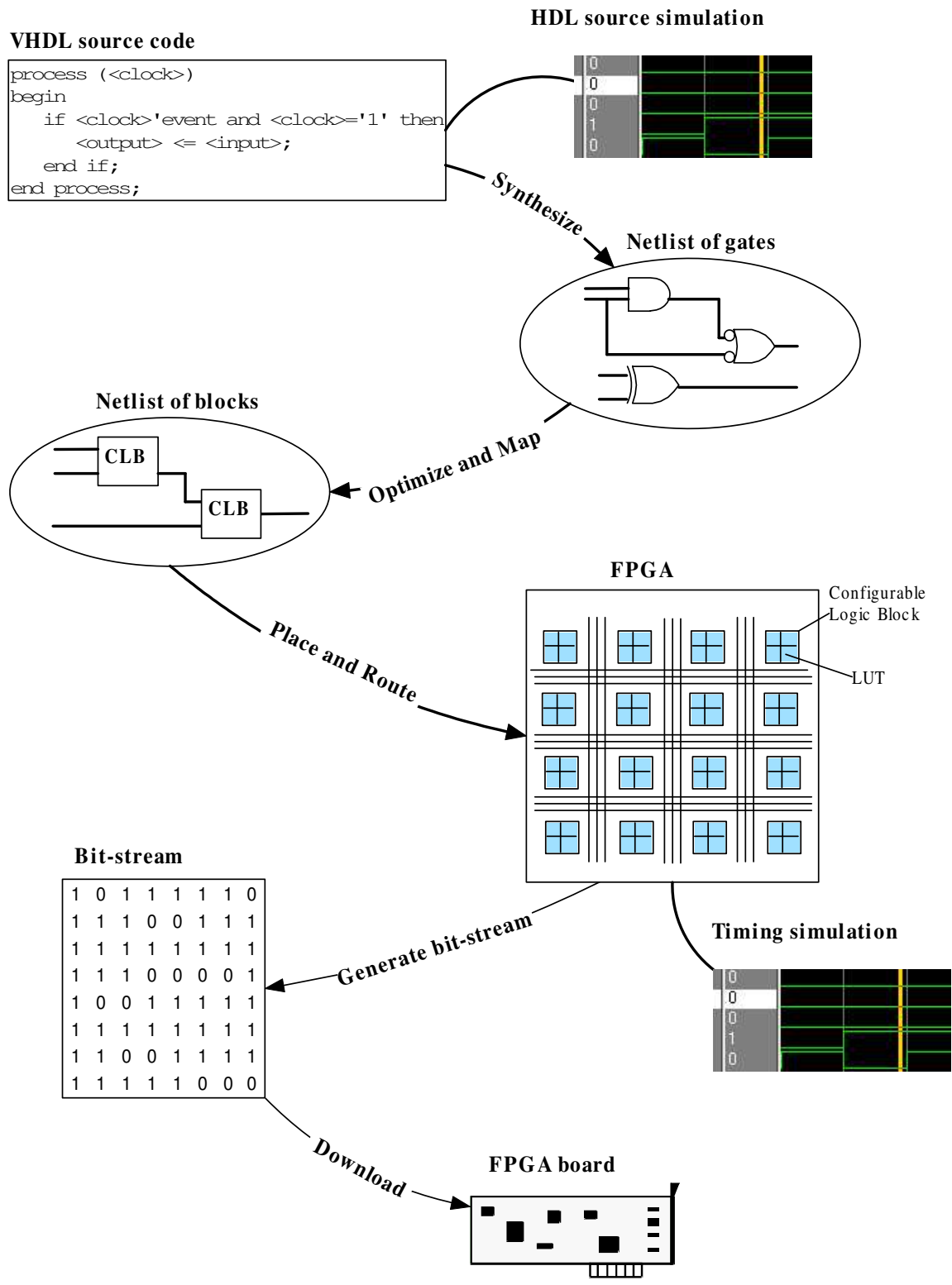


Figure 2.6: Design steps with FPGAs.



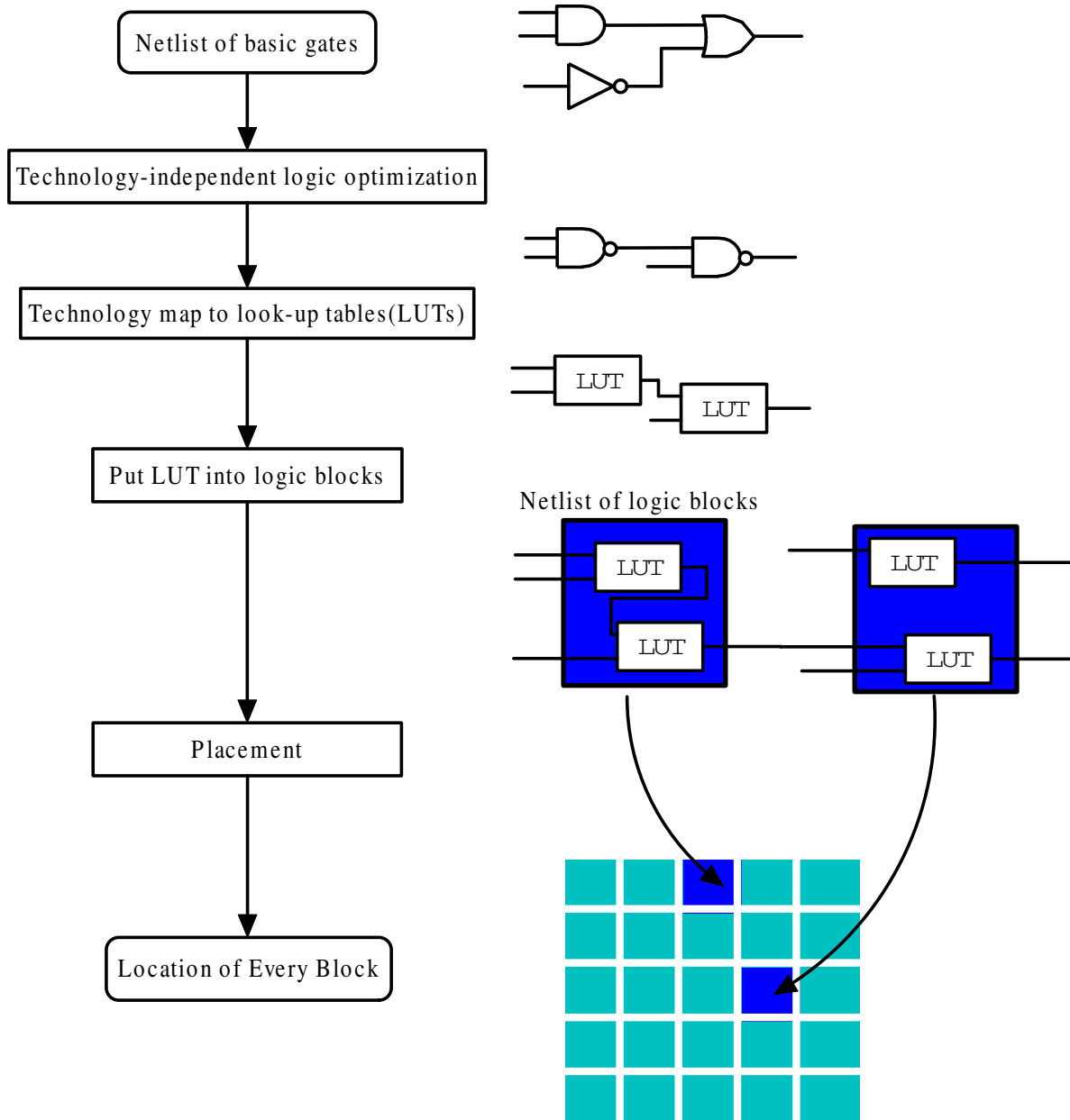


Figure 2.7: Details of synthesis, map and placement.

## CHAPTER 3

### OVERVIEW OF THE VERSATILE PLACE AND ROUTE TOOL

The Versatile Place and Route (VPR) suite is a placement and routing tool developed at the University of Toronto. It is considered as the state-of-the-art academic system to explore placement, routing and architecture for island-style field programmable gate arrays (FPGAs). The framework of VPR was setup by Vaughn Betz and Jonathan Rose. Later Alexander Marquardt added timing driven placement to this suite. VPR is capable of producing a compact lay out for a given circuit.

To use VPR, we should provide four required parameters in addition to many optional parameters; it is invoked by typing [3]:

```
vpr netlist.net architecture.arch placement.p routing.r [-options]
```

Netlist.net and architecture.arch are input files, while placement.p and routing.r are output files. Netlist.net describes the netlist of the circuit to be placed and/or routed. Architecture.arch describes the architecture of the FPGA on which the circuit is to be implemented. By default, VPR first places the circuit and writes the placement to file placement.p. Then it routes the circuit according to the placement and outputs the routing result to file routing.r.

VPR has two basic running modes. In its default mode, VPR places a circuit on an FPGA and then repeatedly attempts to route it in order to find the minimum number of tracks on the given FPGA architecture. In the other mode, VPR is invoked with a user-specified channel width and it reports the circuit can be routed or not [3].

VPR can perform combined global and detailed routing. The key metrics in file routing.r include critical path delay, channel width and wirelength. These three metrics determine the overall performance of a post-routing circuit.

### 3.1. FPGA Architecture File (.arch)

Architecture file defines the attributes and capabilities of an FPGA device. It includes four categories of parameters: configurable logic block (CLB, which corresponds to logic block in VPR), global routing, detailed routing, and timing. Each line in an architecture file specify an attribute which is a keyword followed by one or more parameters. In this section, we will analyze a sample architecture file from VPR website [41]. This FPGA architecture file is widely used in published research papers related to VPR. We will examine these 4 categories one by one.

#### 3.1.1. *Configurable Logic Block*

```
inpin class: 0 bottom
inpin class: 0 left
inpin class: 0 top
inpin class: 0 right
outpin class: 1 bottom right
inpin class: 2 global top      #Clock; shouldn't matter.

subblocks_per_clb 1
subblock_lut_size 4
```

This part defines the internal structure of each CLB. In this example, each CLB contains only 1 subblock which consists of a 4-input look-up table (LUT), 1 flip-flop, and a multiplexer. A subblock is call a basic logic element (BLE) in VPR. LUT is defined by its inputs first, then output, then clock. Each input pin appears on one side of a CLB, while the output is on the bottom and right sides. Figure 3.1 shows the CLB architecture specified by the above definitions.

Note that all the 4 LUT inputs are filled with blue color. There are 4 CLB pins on the edges of this CLB which are also filled with blue color. We can connect any LUT input to any of these 4 CLB pins without changing the logic function. This means you can permute the

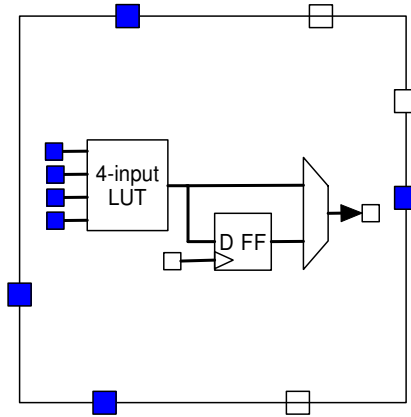


Figure 3.1: CLB and its subblock.

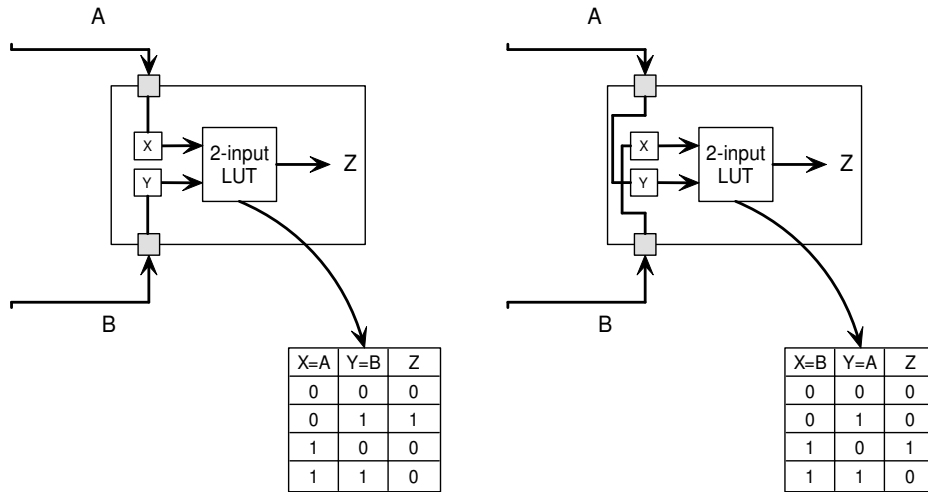
external wires connected to these 4 LUT inputs arbitrarily and still get the desired output. Figure 5(b) shows an example why this is possible. Assume the external wires are named  $A$  and  $B$ . Figure 2(a) is the truth table we want to implement. Figure 2(b) presents one solution in which  $A$  is connected to pin  $X$ , and  $B$  is connected to pin  $Y$ . Since  $X$  equals  $A$  and  $Y$  equals  $B$ , so the LUT table should be the same as the truth table in 2(a). Figure 2(c) presents another solution in which  $A$  is connected to pin  $Y$ , and  $B$  is connected to pin  $X$ . Since  $X$  equals  $B$  and  $Y$  equals  $A$ , so for every entry  $(x, y)$  in the LUT table, its value is the output of entry  $(y, x)$  in the truth table in 2(a). As a conclusion, an external wire can be connected to any pin in the same class without changing the logic function. Only the LUT table and local connection should be modified. So these 4 CLB pins are logically equivalent and are declared to be in the same class.

### 3.1.2. Global Routing

```
io_rat 2
chan_width_io 1
chan_width_x uniform 1
chan_width_y uniform 1
```

A	B	Out
0	0	0
0	1	1
1	0	0
1	1	0

(a) Truth table.



(b) Post-routing layout.

(c) Post-routing layout after switching A and B.

Figure 3.2: Pin in the same class.

This part defines the global routing attributes of an FPGA. In this example, *io\_rat* 2 means there are two input/output (IO) pads per row or column. *chan\_width\_io* 1 means the width of the channels between the pads and core relative to the widest core channel is 1. That is, the boarder channels are as wide as the channels at the center of the FPGA. Similarly, we can conclude that all x-directed, y-directed channels, and boarder channels are of the same width. Figure 3.3 shows the definitions of these terminologies and a sample 4x4 FPGA satisfying these four lines of definition.

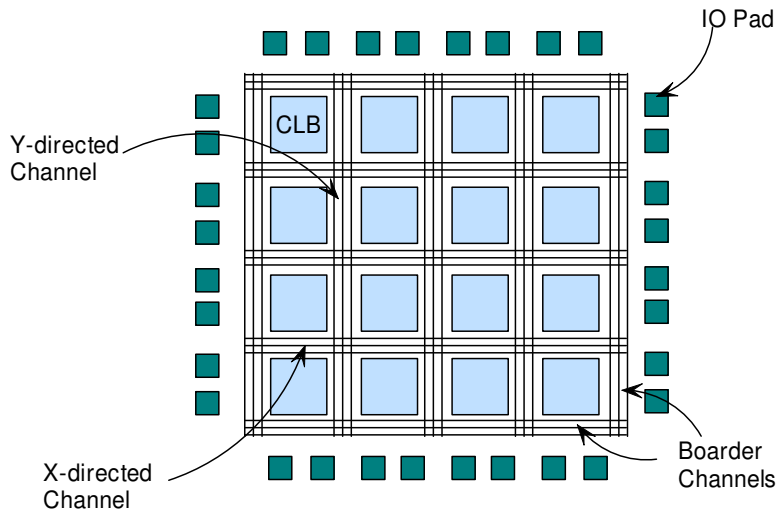


Figure 3.3: Global routing parameters.

### 3.1.3. Detailed Routing

```
switch_block_type subset
Fc_type fractional
Fc_output 1
Fc_input 1
Fc_pad 1
```

The type of switch block used in this architecture is *subset*. A subset switch box is the planar switch box used in the Xilinx 4000 FPGAs – a wire segment in track 0 can only connect to other wire segments in track 0 and so on. Figure 3.4 shows the topology of a subset type switch.

$Fc\_output$ ,  $Fc\_input$  and  $Fc\_pad$  are all 1 which means the input/output pin of a CLB or an IO pad can be connected to every track in the channel bordering the pin.

```
segment frequency: 1 length: 1 wire_switch: 0 opin_switch: 0 Frac_cb: 1. \
  Frac_sb: 1. Rmetal: 4.16 Cmetal: 81e-15
```

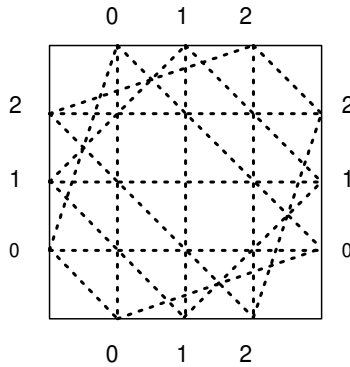


Figure 3.4: A subset type switch.

```
switch 0 buffered: yes R: 786.9 Cin: 7.512e-15 Cout: 10.762e-15 Tdel: 456e-12
```

The segment definition gives the following information:

- The length of all wires in this FPGA is 1.
- The switch type used by other wiring segments to drive this segment is *switch 0*.
- The resistance per unit length (in terms of logic blocks), in Ohms, is 4.16.
- The capacitance per unit length (in terms of logic blocks), in Farads, is 81e-15.

The only available switch type is *switch 0*, which uses tri-state buffer. Its resistance is 786 Ohms, its input capacitance is 7.52e-15 F, its input capacitance is 10.762e-15 F, and its delay is 456e-12 s.

#### 3.1.4. Timing Parameters

```
C_ipin_cblock 7.512e-15
T_ipin_cblock 1.5e-9
T_ipad 478e-12 # clk_to_Q + 2:1 mux
T_opad 295e-12 # Tsetup
T_sblk_opin_to_sblk_ipin 0 # No local routing
T_clb_ipin_to_sblk_ipin 0 # No local routing
T_sblk_opin_to_clb_opin 0.
```

The most important parameters are  $C_{ipin\_cblock}$  and  $T_{ipin\_cblock}$ .  $C_{ipin\_cblock}$  is the input capacitance of the buffer isolating a routing track from the connection boxes (multiplexers) which select the signal to be connected to an logic block input pin.  $T_{ipin\_cblock}$  is the delay to go from a routing track, through the isolation buffer and a connection block to a logic input pin [3]. All other timing parameters are related to local connection delay and are much less than  $T_{ipin\_cblock}$ . They are not as important as  $T_{ipin\_cblock}$  in timing analysis.

### 3.2. Circuit Netlist File(.net) Format

The netlist file provides connection information like how many blocks each logic block connects to and who are these other blocks. There are three different circuit elements in a netlist file: input pads, output pads, and logic blocks, which are specified using the keywords `.input`, `.output`, and `.clb`, respectively. The format is shown below:

```
.input/.output/.clb blockname
  pinlist: net_0 net_1 net_2 ...
  # Only needed if a clb
  subblock: subblock_name pin_num0 pin_num1 ... #BLE0
  [subblock: subblock_name pin_num0 pin_num1 ...] #BLE1
...
```

The first line describes the type and name of this block. The second line begins with the identifier of the pinlist, and then lists the names of the nets connected to each pin of the logic block or pad. Input or output pads(`.inputs` and `.outputs`) have just one pin, while logic blocks (`.clbs`) have as many pins as the architecture file specifies. The first net listed in the pinlist is connected to pin 0 of a CLB, and so on. If some pin of a CLB is left unconnected, the corresponding entry in the pinlist should be labeled as *open*. CLBs (`.clbs`) also have to specify the internal connections with subblock lines. Each CLB has at least one



subblock line, and may have up to *subblocks\_per\_clb* subblock lines, where *subblocks\_per\_clb* is specified in the architecture file.

Each subblock contains a  $K$ -input LUT (where  $K$  is set via the *subblock\_lut\_size* line in the architecture file) and a flip flop, as shown in Figure 3.1 where  $K$  is 4. The subblock line specifies the name of the subblock, followed by a list of pin names. The first pin, *pin\_num0*, is a CLB pin or a subblock output pin connected to BLE pin 0. So do the remaining pin names. If a BLE pin is unconnected, the corresponding pin entry is set to the keyword *open*. The order of the BLE pins is: *subblock\_lut\_size* LUT input pins, the BLE output, and the clock input. Each of the subblock LUT input pins can be connected to any of the CLB input pins, or to the output of any of the subblocks in this CLB. If its is connedted to a CLB input pin, only the index of this CLB pin is specified. If it is connected to a subblock output, the entry should be written as *ble\_ < subblock\_number >*. For example, to connect to CLB pin 2, one lists 2 in the appropriate place, while to connect to the output of subblock 1, one lists *ble\_1* in the appropriate place. Note that we only need to provide the index of the subblock because a subblock has only one output pin. Each subblock clock pin can also be connected to either a CLB input pin or the output of a subblock in the same logic block. If the subblock clock pin is open the BLE output is the unregistered LUT output; otherwise the BLE output is registered. The entry corresponding to the subblock output pin specifies the index of the CLB output pin to which it connects, or open if this subblock output does not connect to any CLB output pin (It does not mean this output pin is not connected; it means this subblock output is only used locally, within this CLB).

### 3.2.1. An Example Circuit

```
.input i_0
    pinlist: i_0
.input i_1
    pinlist: i_1
.input i_2
```

```

    pinlist: i_2
.input i_3
    pinlist: i_3
.input clk
    pinlist: clk
.global clk

.clb clb_0 # Only LUT used.
    pinlist: i_0 i_1 i_2 i_3 [0] clk
    subblock: sb_zero 0 1 2 3 4 5
.clb clb_1 # Only LUT used.
    pinlist: i_4 i_5 i_6 i_3 [1] clk
    subblock: sb_zero 0 1 2 3 4 5
.clb clb_2 # Only LUT used.
    pinlist: [0] [1] open open o_0 clk
    subblock: sb_zero 0 1 open open 4 5

.input i_4
    pinlist: i_4
.input i_5
    pinlist: i_5
.input i_6
    pinlist: i_6
.output out:o_0
    pinlist: o_0

```

This sample circuit (seq\_s.net) consists of 7 inputs ( $i_0$  to  $i_6$ ), 3 logic blocks ( $clb_0$  to  $clb_2$ ), and an output ( $o_0$ ). Figure 5(a) shows the corresponding real circuit. The label inside each logic block is the name of this block. The label on each wire is the name of this wire. When we invoke VPR using the following commands:

```
vpr seq_s.net challenge.arch seq_s.p seq_s.r
```

It will produce the placement file named `seq_s.p` and routing file `seq_s.r`. Figure 5(b) shows the post-routing layout of this circuit which is equivalent to the content of `seq_s.net`. We can see the channel width of this circuit is 2.

### 3.3. Placement File

The first line of the placement file shows the netlist (`.net`) and architecture (`.arch`) files used to create this placement. The second line gives the number of rows and columns of the CLBs used by this placement. All the remaining lines are in the following format [3]:

```
block_name x y subblock_number
```

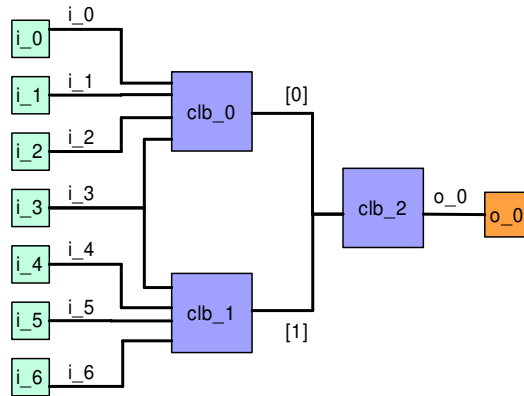
The *block\_name* is the name of this block, as it appears in the input netlist. This block is placed at row *x* and column *y*. The subblock number is meaningful only for IO pads. Because *io\_rat* is set to 2 in the example architecture file shown in Section 3.1, a pad location (*x*, *y*) may contain 2 IO pins. A IO pad may reside in any of the *io\_rat* number of possible pad locations in (*x*, *y*), and the location is specified by *subblock\_number*. Note that the possible pad locations at (*x*, *y*) are used from 0 to *io\_rat* - 1 in order, i.e., if only one pad at (*x*, *y*) is used, the *subblock\_number* of the IO pin placed there will be 0. For CLBs, the subblock number is always 0.

Figure 3.6 shows the coordinate system used by VPR via a  $nx \times ny$  CLB FPGA ( $nx = ny = 2$ ). CLBs all go in the area with *x* between 1 and *nx* and *y* between 1 and *ny*, inclusive. All pads either have *x* equal to 0 or *nx* + 1 or *y* equal to 0 or *ny* + 1.

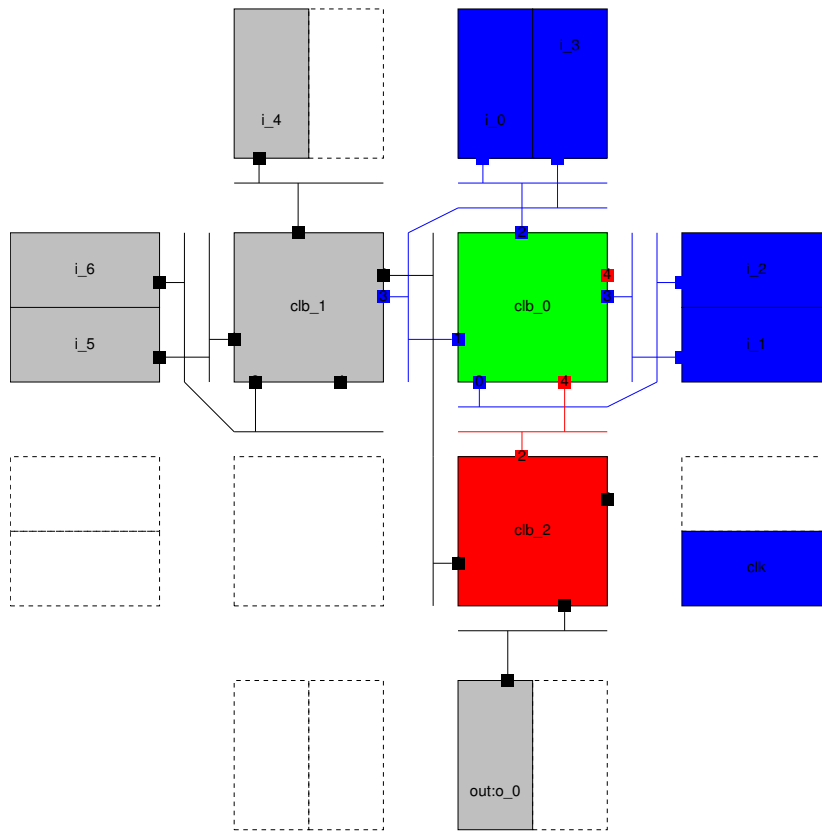
The placement file `seq_s.p` produced by VPR for the `seq_s.net` input is given below. We can match it to Figure 5(b). For example, the coordinates for the input pad `i_0` is (2,3) in `seq_s.p`, and we can find it top right most in Figure 5(b). For IO pins, we can find `i_0` and `i_3` are both located at position (2,3).

```
Netlist file: seq_s.net   Architecture file: simple.arch
```

```
Array size: 2 x 2 logic blocks
```



(a) The netlist input.



Block 5 (clb\_0) at (2, 2) selected.

(b) The post-routing layout

Figure 3.5: The netlist input of a circuit and its post routing layout.

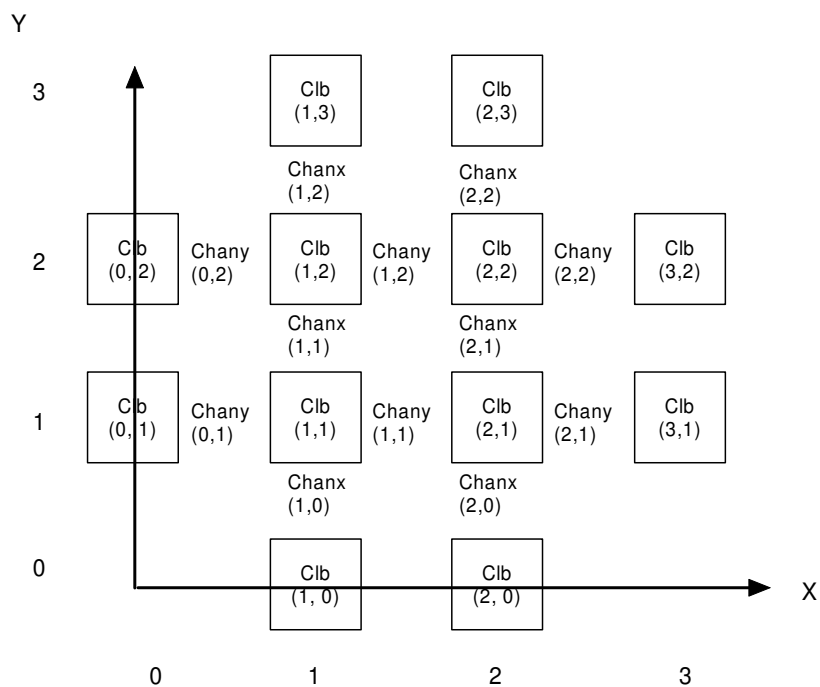


Figure 3.6: Coordinate system in VPR.

#block name	x	y	subblk	block number
i_0	2	3	0	#0
i_1	3	2	0	#1
i_2	3	2	1	#2
i_3	2	3	1	#3
clk	3	1	0	#4
clb_0	2	2	0	#5
i_4	1	3	0	#6
i_5	0	2	0	#7
i_6	0	2	1	#8
clb_1	1	2	0	#9
clb_2	2	1	0	#10
out:o_0	2	0	0	#11

## CHAPTER 4

### CONGESTION DRIVEN PLACEMENT

There are three major classes of placers in use today: min-cut (partitioning) based placer [16, 19, 46], analytic placer [1, 2, 36, 45, 50, 52, 51], and simulated annealing based placer [35, 48, 49, 47, 53, 54, 51]. The Versatile Place and Route (VPR) tool uses simulated annealing method in its placement phase. My proposed algorithms in this thesis are all integrated into the framework of VPR. I will discuss the details of VPR in the following section.

#### 4.1. Placement in VPR

VPR uses a generic simulated annealing algorithm which is shown in Algorithm 4.1.

The key element in a simulated annealing based algorithm is the cost function. The following auto-normalizing cost function is used in VPR's placement algorithm [40]:

$$(1) \quad \Delta C = \lambda \cdot \frac{\Delta C_T}{Previous\_C_T} + (1 - \lambda) \cdot \frac{\Delta C_W}{Previous\_C_W}$$

where  $C_T$  is the timing cost,  $C_W$  is the wiring cost, and  $\lambda$  is a user defined constant between 0 and 1 which trades off between timing cost and wiring cost. By default,  $\lambda$  is 0.5.  $Previous\_C_T$  and  $Previous\_C_W$  are updated at the beginning of every temperature and used by all moves at this temperature. The equations to compute  $C_T$  are given below [40]:

$$(2) \quad C_T = \sum_{\forall i, j \in circuit} C_T(i, j)$$

$$(3) \quad C_T(i, j) = Delay(i, j) \cdot Crit(i, j)^{Exp}$$

$$(4) \quad Crit(i, j) = 1 - \frac{Slack(i, j)}{D_{max}}$$

**Algorithm 4.1.1:** SAPLACER()

```

S ← RandomPlacement();
T ← InitialTemperature();
Rlimit ← InitialRadius();
while(ExitCriterion() == FALSE)
{
  while(NeedToUpdateTemperature() == FALSE)
  {
    Snew ← NewPlacementByMove(S, Rlimit);
     $\Delta C$  ← Cost(Snew) − Cost(S);
    r ← random(0, 1);
    if(r <  $e^{-\Delta C/T}$ )
      S ← Snew;
  }
  T ← UpdateTemperature();
  Rlimit ← UpdateRadius();
}

```

where  $C_T(i, j)$  is the timing cost for each *edge*  $(i, j)$ , and the definitions of  $Delay(i, j)$ ,  $D_{max}$ , and  $Slack(i, j)$  are described in Chapter 5 where I explain the details of timing analysis. The *Exp* factor is constant at each temperature. It gradually increases from 1 to 8 from the beginning to the end of the process of simulated annealing. The purpose of including an exponent on the *Crit* is to heavily weight connections that are critical, while giving less weight to connections that are non-critical.

The wiring cost is defined as [40]:

$$(5) \quad C_W = \sum_{i=1}^{N_{nets}} q[i](bb_x(i) + bb_y(i))$$

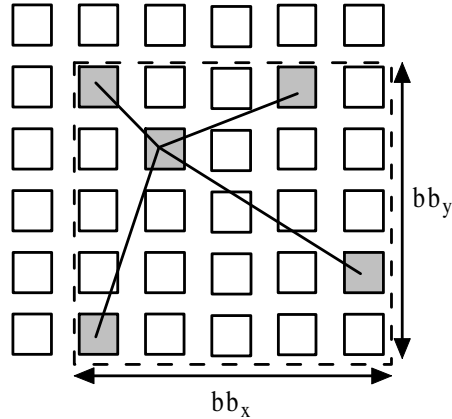


Figure 4.1: Example of a bounding box of a 5 terminal net in an FPGA.

where  $N_{nets}$  is the total number of nets in the circuit. For each net  $i$ ,  $bb_x(i)$  is its horizontal span, and  $bb_y(i)$  is its vertical span. Figure 4.1 shows the bounding box of a 5-terminal net. The  $q(i)$  factor compensates for the fact that the bounding box wire length model usually underestimates the wiring necessary to connect nets with more than three terminals. The appropriate values of  $q(i)$  are obtained from [9].

#### 4.2. Congestion Metric

From the above analysis we can see that the mutual interactions of different nets are not taken into account by VPR's linear congestion method. In this section, I present my method to overcome this drawback and give a detailed algorithm.

To reduce the routing channel width, a placement algorithm has to pay attention to both the resource consumed by each net, and the interaction (congestion) among different nets. The first consideration is to shrink every net as much as possible, since a net expanding too much needs a lot of wire segments and will increase global congestion. The second consideration is to disperse different nets as far as possible, because overlapping nets will add to local congestion. For example, if all nets are restricted to a relatively small fraction of area on the chip, the routing track demand will probably be very high in this region. Although configurable logic blocks (CLBs) in other regions may be easily routed with a



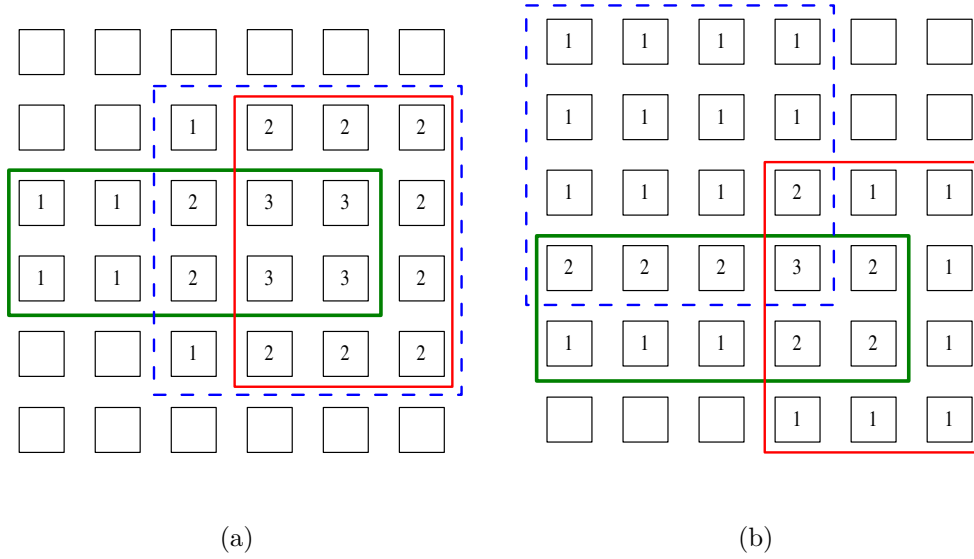


Figure 4.2: A circuit with three overlapping bounding boxes: a) Placement may result in a congested routing. b) Placement leads to a balanced routing. My goal is to achieve (b).

small channel width, the overall channel width is still determined by the channel that uses the maximum number of tracks if all channels are of the same width.

In my algorithm, I formulated a new wiring cost function. I define a new metric which evaluates the congestion uniformity of a placement over the entire chip. The final wiring cost is now computed by multiplying the previous Wiring Cost  $C_W$  with my congestion coefficient *Congestion* (defined in Equation (7)), that is

$$(6) \quad C'_W = \text{Congestion} \cdot C_W$$

First, I introduce the congestion model used in my algorithm. Assume a circuit consisting of 3 nets is to be placed. An intermediate placement during the simulated annealing process is shown in Figure 2(a). The 3 bounding boxes are shown by different rectangles. The number in each CLB indicates how many bounding boxes are covering this CLB at this moment. A CLB without a label is not covered by any bounding box (i.e., it is labeled with

0). For example, a CLB with label 2 means it is covered by the bounding boxes of two nets. Since every net will probably need some routing tracks around the CLBs it covers, the regions covered by more bounding boxes would require more routing resources. In Figure 2(a), the CLBs with label 3 are very likely to be the bottleneck to reduce channel width. Another placement shown in Figure 2(b) provides a better solution even though the dimension of each bounding box remains unchanged. In Figure 2(b), the congestion is dispersed so that channel width can be reduced.

The following formula is used in my algorithm to compute the congestion coefficient,

$$(7) \quad Congestion = \left( \frac{\sum_{i,j} U_{i,j}^2}{nx \cdot ny} / \left( \frac{\sum_{i,j} U_{i,j}}{nx \cdot ny} \right)^2 \right)^k, \quad 1 \leq i \leq nx, 1 \leq j \leq ny,$$

where  $U_{i,j}$  is the number of bounding boxes covering  $CLB_{i,j}$ ,  $k$  is a constant integer for each circuit ( $k$  can be either 2 or 1 and the picking criteria is discussed in Section 5.4), and the chip consists of  $nx$  by  $ny$  CLBs.

As we know, for  $n$  positive numbers  $a_1, a_2, \dots, a_n$ , the expression  $uniform = \frac{\sum_{i=1}^n a_i^2/n}{(\sum_{i=1}^n a_i/n)^2}$  has two properties

- (i)  $uniform \geq 1$ . This is true because arithmetic mean is always equal to or greater than geometric mean.
- (ii) A balanced set of  $a_i$  will give a small  $uniform$ . For example, assume  $n = 4$ , consider two set of  $a_i$ ,  $A1 = \{1, 2, 3, 4\}$ ,  $A2 = 2, 2, 3, 3$ . The sum of all elements in  $A1$  is 10, the same as of  $A2$ . But the  $uniform$  of  $A1$  is 1.2 which is greater than the  $uniform$  of  $A2$  (1.04), since the elements in  $A2$  are closer to each other.

So,  $Congestion$  is always equal to or greater than 1. In Equation (7), if  $\sum U_{i,j}$  remains constant,  $Congestion$  is determined only by  $\sum U_{i,j}^2$ . A balanced set of  $U_{i,j}$  will give a small  $Congestion$ . So the value of  $Congestion$  indicates how congested the final placement is expected to be. When it is close to 1, the placement is balanced. If it is much greater than 1, the placement is considered congested.

Now let us examine my algorithm on the placements shown in Figure 4.2. Assume  $k = 1$ , apply Equation (7) to Figure 2(a) and Figure 2(b), we can compute the congestions are  $Congestion_a = 2.04$ , and  $Congestion_b = 1.446$  respectively. As a result, a placement in Figure 2(b) is favored by my algorithm and CLBs are dispersed more evenly across the whole chip. The final channel width is very likely be reduced.

Algorithm 4.3.1 is the pseudocode of my proposed algorithm. Function “compBBCost()” calculates the final wiring cost according to the circuit-specific constant  $k$ . Function “getBoundingBox()” computes the bounding box for each net and stores its dimension and location in  $bb[i]$ . Function “getNetCost()” obtains the original bounding box cost computed by VPR using Equation (5), and function “congestionFunc()” calculates the *Congestion* factor.

The computation complexity of a single swap is  $O(n^2)$  in my algorithm. Considering there are millions of swap in the process of simulated annealing, a trivial implementation will cost too much runtime. In chapter 6, I provide several techniques to address this problem.

### 4.3. Experimental Results

I have implemented and integrated my proposed algorithm in the framework of VPR. The experiments were carried out on an Intel Pentium®-4 2.8GHz PC with 1GB memory running the CentOS Linux system. The netlist files of the 20 Microelectronics Center of North Carolina (MCNC) benchmark circuits and the VPR source code (version 4.3) were downloaded from [42]. I use gcc 3.4.5 to compile all the source codes.

Table 4.1 shows the experimental results of VPR and my congestion approach. Figure 4.3 gives the corresponding chart. All results are normalized to VPR. Compared with VPR, my algorithm reduces channel width by 7.1% and reduces critical path delay by 0.7%. Although my approach does not degrade timing in average, it is not preferable that the critical path delays of several circuits are elongated a lot, such as circuit “alu4”, “apex2”, and “bigkey”. This problem is addressed in chapter 5.

**Algorithm 4.3.1: COMPUTING BOUNDING BOX COST( $t$ )**

```
procedure COMPBBCOST( $k$ )  
  CLEARBLKUSAGE( $U$ )  
   $cost \leftarrow 0$   
  for  $n \leftarrow 0$  to  $num\_nets$   
    GETBOUNDINGBOX( $bb[n]$ )  
    for  $i \leftarrow bb[n].xMin$  to  $bb[n].xMax$   
      for  $j \leftarrow bb[n].yMin$  to  $bb[n].yMax$   
         $U[i, j] \leftarrow U[i, j] + 1$   
       $cost \leftarrow cost + GETNETCOST(n)$   
   $congestion \leftarrow CONGESTIONFUNC(U, k)$   
  return ( $cost * congestion$ )
```

```
procedure CONGESTIONFUNC( $U, k$ )  
   $sum \leftarrow 0$   
   $sos \leftarrow 0$   
  for  $i \leftarrow 1$  to  $nx$   
    for  $j \leftarrow 1$  to  $ny$   
       $sos \leftarrow sos + U[i, j] * U[i, j]$   
       $sum \leftarrow sum + U[i, j]$   
   $base \leftarrow sos * nx * ny / sum^2$   
  return ( $base^k$ )
```

Table 4.1: Experiment results: VPR, VPRb and my algorithm.

Circuit	VPR		VPRb				Mine					
	CP	CW	CP	Ratio	CW	Ratio	CP	Ratio	CW	Ratio	minExp	maxExp
tseng	55.62	8	71.56	1.2866	7	0.875	53.65	0.9646	7	0.875	1	2
apex4	93.25	14	131	1.4048	13	0.9286	92.75	0.9946	13	0.9286	1	3
misex3	95.74	12	107.7	1.1249	11	0.9167	82	0.8565	11	0.9167	1	3
dsip	70.79	7	82.14	1.1603	6	0.8571	66.62	0.9411	6	0.8571	1	4
ex1010	195.3	12	206.1	1.0553	10	0.8333	182.6	0.935	11	0.9167	2	4
clma	228.4	14	243.7	1.067	13	0.9286	213.7	0.9356	13	0.9286	3	5
diffeq	101.5	8	93.38	0.92	7	0.875	63.44	0.625	8	1	1	3
spla	203.1	15	181	0.8912	14	0.9333	158.9	0.7824	15	1	1	4
seq	95.72	12	109.7	1.1461	12	1	81.65	0.853	12	1	1	3
elliptic	137.2	12	187.1	1.3637	11	0.9167	126.8	0.9242	11	0.9167	1	4
pdc	193.5	19	211.3	1.092	17	0.8947	198.9	1.028	17	0.8947	2	4
frisc	135	14	176	1.3037	12	0.8571	142.7	1.057	13	0.9286	1	4
bigkey	78.56	7	88.7	1.1291	7	1	99.46	1.266	6	0.8571	1	4
des	121.2	8	114.7	0.9464	8	1	124.2	1.0248	7	0.875	1	4
alu4	82.1	11	121.7	1.4823	10	0.9091	98.93	1.205	10	0.9091	1	3
apex2	90.02	12	134.8	1.4974	11	0.9167	111.8	1.242	11	0.9167	1	3
ex5p	84.06	15	129.4	1.5394	13	0.8667	87.1	1.0362	13	0.8667	1	1
s298	135.7	8	204	1.5033	8	1	148.5	1.0943	8	1	1	4
s38417	103.3	8	156.9	1.5189	7	0.874	112.3	1.087	8	1	2	5
s38584.1	97.92	8	126.7	1.2939	8	1	98.21	1.003	8	1	2	5
Ave				1.2363		0.9192		0.9928		0.9294		

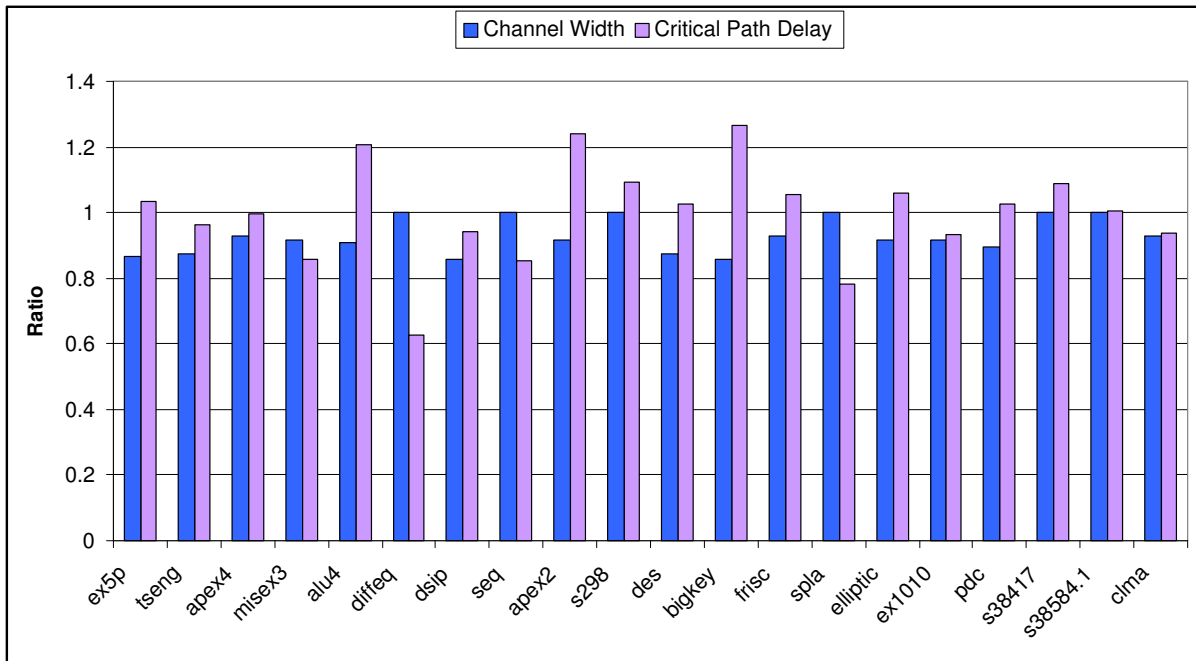


Figure 4.3: Ours (congestion driven) vs. VPR.

## CHAPTER 5

### TIMING DRIVEN PLACEMENT

#### 5.1. Timing Analysis

Timing-driven placement algorithms attempt to place circuit blocks that are on the critical path into physical locations that are close together. Timing-driven approaches can minimize the amount of interconnect that the critical signals must traverse. In placement, timing-driven algorithms can be broadly divided into two classes: path-based and net-based.

Path-based algorithms try to compute the delay of all paths and directly minimize the longest path delay [17, 33, 51]. This class of techniques are generally based on mathematical programming and iterative critical path estimation. Path-based algorithms can give an accurate timing view during the optimization procedure. However, the major drawback is its high computation complexity due to the exponential number of paths which need to be simultaneously considered.

Net-based algorithms, on the contrary, do not handle path-based constraints directly [15, 37, 40, 43, 58]. They usually transform timing constraints on paths into either net-length or net-weight constraints. A popular approach is called *net-weighting* method. In such approaches, static timing analysis is applied at intermediate phases and nets are assigned criticality weights; higher weights are assigned to nets which are more timing critical. After that moment until the next timing analysis, the criticality of an edge does not change even its two terminals may be moved.

To perform net-weighting analysis, a directed graph  $G(V, E)$  representing the circuit is constructed. Each wire and each logic block pin becomes a node in the graph, where a pin comes from a look-up table (LUT), a register, or an input/output (IO) pad. Each switch becomes a directed edge or a pair of directed edges between two appropriate nodes. Every

edge is annotated with a physical delay between the nodes. Figure 5.1 shows an example of a circuit and its timing analysis graph. A *source* is the pin of an input pad or a register output, while a *sink* is the pin of an output pad or a register input. Each *path* starts at a source and ends at a sink. Given a node  $j$ , the *arrival time*,  $Arr(j)$ , is the time at which the signal at node  $j$  settles to its final value if all primary inputs are stable at time zero. Given a maximum delay constraint, the *required time*,  $Req(j)$ , is the time at which the signal at node  $j$  is required to be stable without elongating the maximum allowed delay.

To determine the arrival time of each node and criticality of each edge, we start from the source nodes and perform a breadth-first traversal on the graph. The arrival time of each node  $j$ ,  $Arr(j)$ , can be computed, iteratively, from the following equation:

$$(8) \quad Arr(j) = \begin{cases} 0, & j \in sources \\ \max\{Arr(i) + Delay(i, j)\}, & (i, j) \in E \end{cases}$$

where  $Delay(i, j)$  is the delay value of the edge connecting node  $i$  and node  $j$ . The maximum arrival time of all nodes in the circuit,  $D_{max}$ , is calculated as

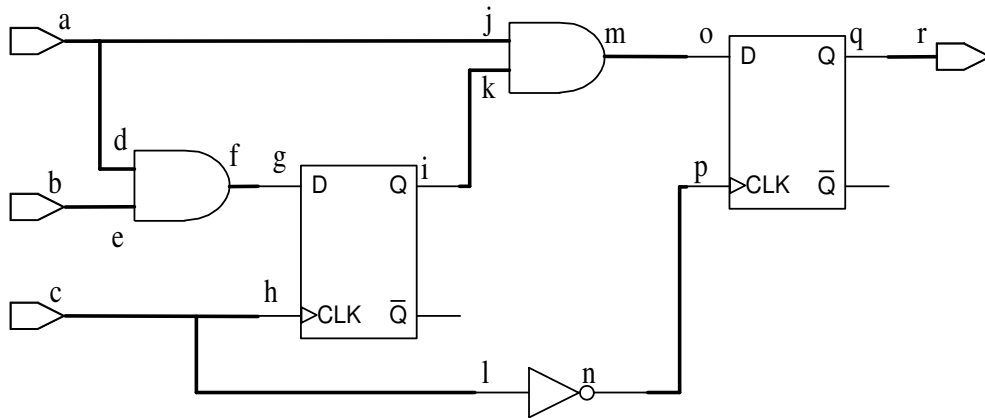
$$(9) \quad D_{max} = \max\{Arr(j)\}, j \in sinks$$

Once  $D_{max}$  is available, the *required arrival time* of each node  $i$ ,  $Req(i)$ , can be computed as follows:

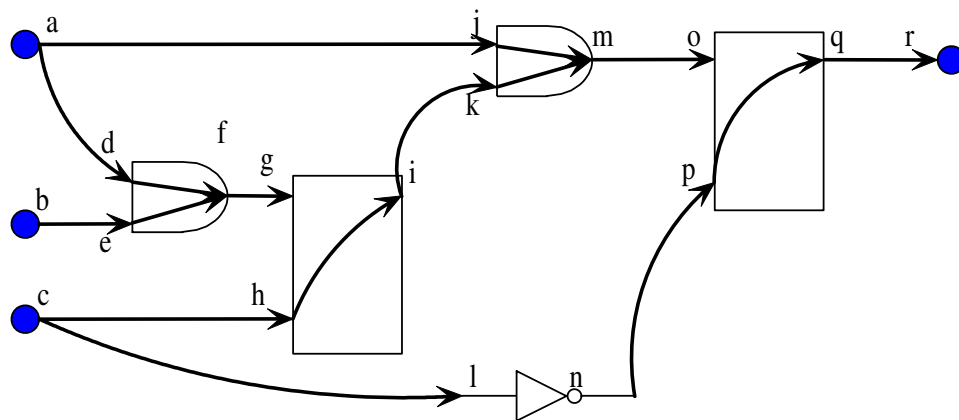
$$(10) \quad Req(i) = \begin{cases} D_{max}, & i \in sinks \\ \min\{Req(j) - Delay(i, j)\}, & (i, j) \in E \end{cases}$$

Finally, we can determine the *slack* of an edge  $(i, j)$ , i.e., the amount of delay that can be added to  $(i, j)$  without causing any path consisting of edge  $(i, j)$  to become the longest path. The slack of edge  $(i, j)$  is computed as follows:





(a) Circuit.



(b) Timing analysis graph.

Figure 5.1: Generic timing analysis graph.

$$(11) \quad \text{Slack}(i, j) = \text{Req}(j) - \text{Arr}(i) - \text{Delay}(i, j)$$

Under this framework, the Versatile Place and Route (VPR) suite utilizes a simulated annealing based method [40]. Kong proposed an efficient all-path counting algorithm called PATH [37]. PATH assigns weight to each edge based on the number and criticality of paths

using this edge. Wang *et al.* tried to improve timing by using linear programming (LP) relaxation [58]. This approach captures all topological paths in a linear sized LP and thus avoids heuristic net weighting. Ren *et al.* proposed a net weighting algorithm considering both *figure of merit* (FOM) and slack sensitivities [43]. Recently, a new technology called *grid-warping* was proposed which elastically deform a model of the 2-D chip surface on which the gates have been roughly placed [61]. Xiu *et al.* designed a timing-driven grid-warping placer [62] using an accurate slack sensitivity analysis method [44] for net weighting.

Differing from the above approaches which work in placement phase, Lin *et al.* proposed an algorithm named SMAC recently optimizing timing during mapping and packing [39]. But this algorithm introduces a high area overhead.

Generally, to simultaneously optimize multiple metrics during placement is very challenging. Most research works can only improve one perspective of the circuit with degradation on other factors. For example, the work in [37] and [58] can improve timing, but the former needs more wire length and the latter results in more channel width. However, some research works improve multiple metrics of the design simultaneously. In [7], Chang *et al.* proposed an architecture-driven metric which pays attention to the number of segments traveled by a net and congestion on segments of specific lengths. In [57], Viswanathan *et al.* proposed a fast, analytical placer, FastPlace 2.0, which reduces wirelength and run time for stand cell placement.

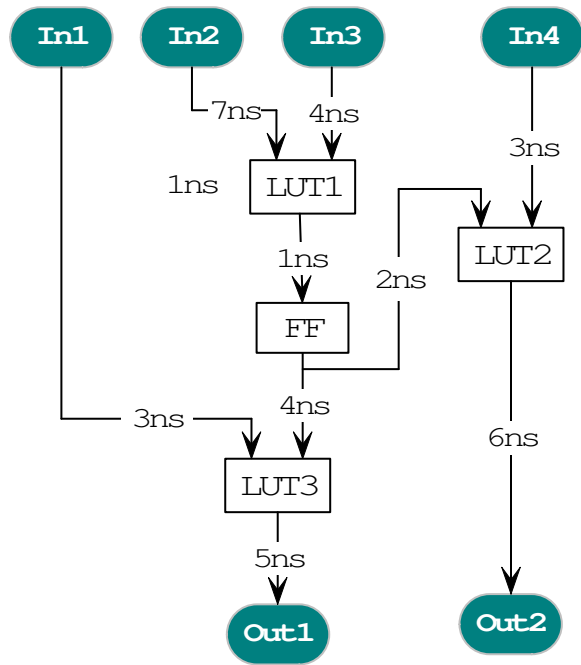
Note that VPR, t-RPack, cMap and Brenner's work all fall into this category. My proposed algorithm also increases circuit speed as well as reduces channel width.

## 5.2. Timing Analysis Graph

Timing analysis graph is the core of every timing-driven placement algorithm. Figure 5.2 shows how VPR constructs a timing analysis graph from a circuit. Figure 2(a) shows a circuit which consists of 4 inputs, 3 LUTs, 1 flip flop and 2 outputs. The delay of each wire is annotated on it. We assume the local delay within each LUT is 1ns, that is, it takes a signal 1ns from it reaches the input pin to get out of the LUT. Figure 2(b) presents the

corresponding graph for timing analysis. Note that register input pins are not joined to register output pins – register outputs have no edges incident to them, and register inputs have no edges leaving them. The reason is when a clock signal arrives, the output of a register is refreshed and begins to excite all its successors. As long as the effected successive signals arrive at the the input of a register or an output pad, they will not interfere with signals in the next clock cycle. Utilizing this method we can break all possible circuits into acyclic directed graph. It can be seen that the timing analysis graph is a forest instead of a tree in general. In Figure 2(b), each edge is annotated with a pair of (*Delay*, *Slack*). The value of *Slack* is computed from Equation (11). Each node is annotated with a pair of (*arrival*, *required*) which are computed from Equation (8) and Equation (10) respectively. Some edge’s slack value is 0 and is labeled using a red color. An edge with zero slack is on the critical path. That means any delay on such an edge will elongate the minimum period needed for the last signal to become stable at the output. We can see in this example there are 6 critical edges and 2 critical paths. In timing analysis, a critical edge or path is paid more attention to than others because they determine the speed of a circuit. By intuition we know a balanced forest is more liable to produce a smaller critical path delay.

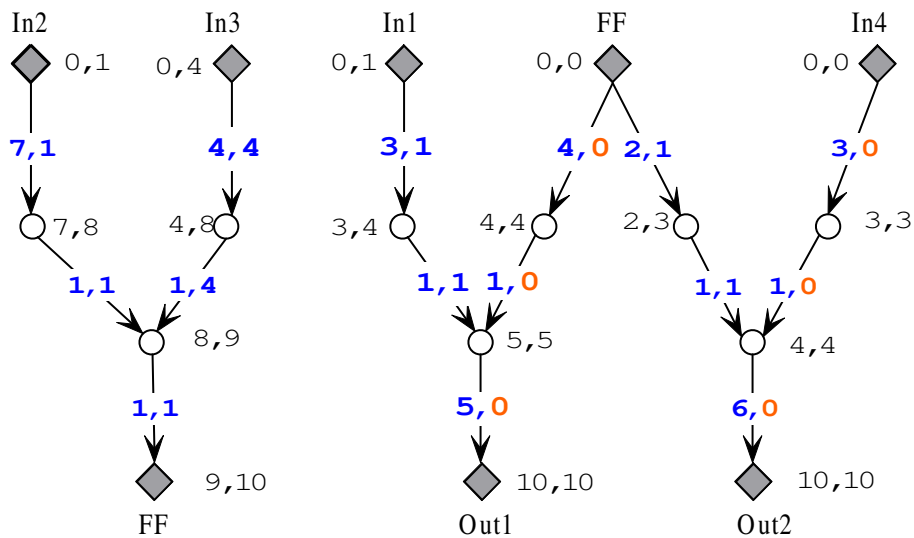
Figure 5.3 gives a more detailed visualization of the timing analysis graph. It shows a typical run time data structure when VPR is performing timing-driven placement. The corresponding input circuit is Figure 5(a) in Chapter 4. There are two nodes for each pin of an input pad. First node is the input node to the pad – nothing comes into this. Second node is the output node of the pad, that has edges to CLB input pins. In addition, global clocks from pads arrive at  $T = 0$ . The earliest any clock can arrive at any flip flop is  $T = 0$ , and the fastest global clock from a pad should have zero delay on its edges so it does get to the flip flop clock pin at  $T = 0$ . Similarly, every pin of an output pad corresponds to two nodes in the graph. When building the subblock input pins, if the subblock is used in sequential mode (i.e. is clocked), two clock pin nodes are created. First node is the clock input pin; it feeds the sequential output. The other node is the "sequential sink", i.e., the



(a) Circuit.

Edge: **Delay, Slack**

Node: Arrival, Required



(b) Timing analysis graph.

Figure 5.2: Timing analysis in VPR.

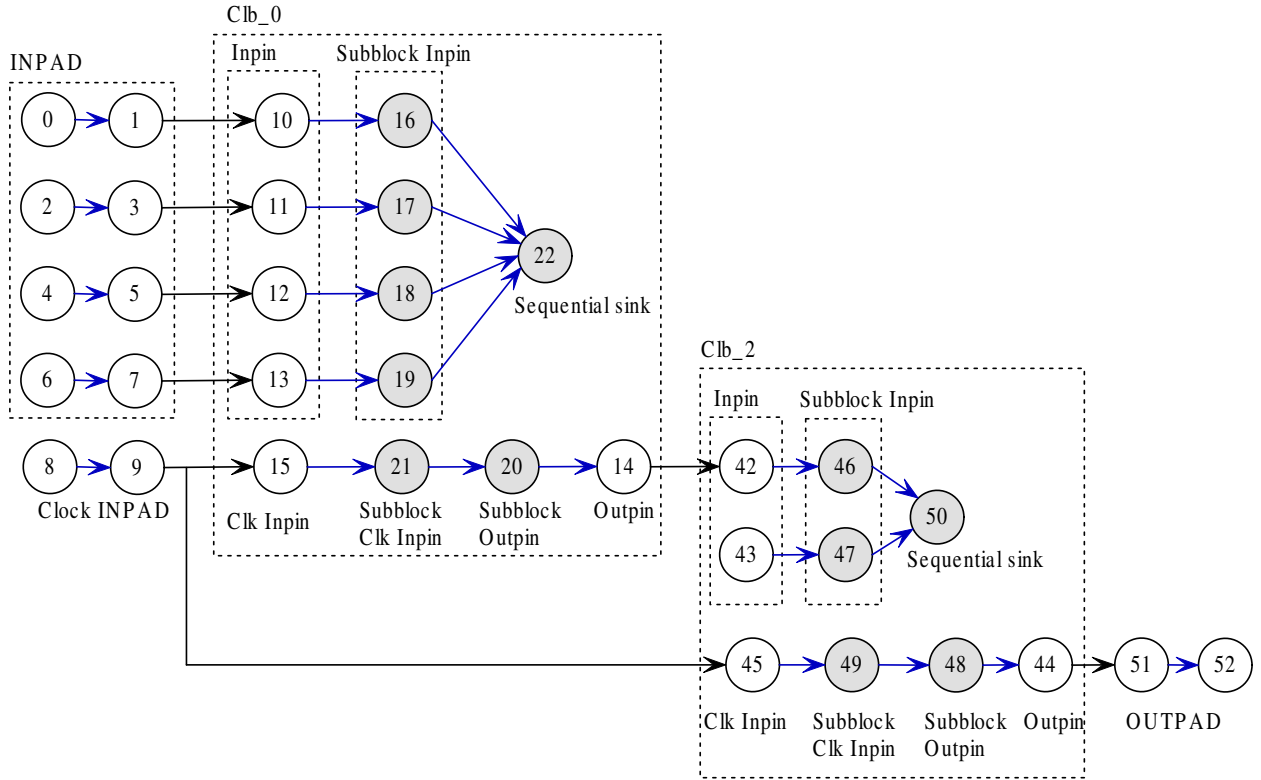


Figure 5.3: Data structures of timing in VPR.

register input node. We can see from this graph that the output of CLB\_1 is connected to the input of CLB\_2. However, in the timing graph, the logic delay of CLB\_1 is not included into the path of CLB\_2. The path from node  $15 \rightarrow 21 \rightarrow 20 \rightarrow 14$  is just the delay to get a new output from the register in CLB\_1.

### 5.3. Criticality History in Timing Analysis

To compare with VPR, I integrate my algorithm into VPR's framework which is based on simulated annealing. I use the same top-level cost function in Equation (1) and the top-level timing cost function in Equation (2). The formulas to compute the timing cost for each edge are modified and shown below:

$$(12) \quad C'_T(i, j) = History(i, j) \cdot C_T(i, j)$$

where  $C_T(i, j)$  comes from Equation (3). The new element in Equation (12) is the  $History(i, j)$  factor, which will be explained below in details.

Since the cost to compute the criticality for each edge from a timing-analysis graph is very high, general timing analysis algorithms can only afford executing this computation once every temperature. As a result, the accuracy becomes less reliable because there are tens of thousands of moves per temperature. The delay of an edge may differ a lot from the original value when the graph was annotated. This is the problem I have addressed in my algorithm.

My approach increases the accuracy without paying much run time penalty. I observed the following two facts: 1) The criticality of a given edge varies in multiple rounds of timing analysis. 2) Some edges are almost always among the most critical edges. In other words, no matter how the configurable logic blocks (CLBs) and IO pads are placed, the criticality value of some edges are always high.

My approach takes advantage of the second phenomenon and thus improves circuit speed. In my algorithm, the criticality value of an edge  $(i, j)$  is accumulated into a variable  $CritStat(i, j)$  every time it is computed. An edge which is often timing-critical will get a high accumulation value. I then favor those historically timing-critical edges by using this statistical data. The accumulation value  $CritStat(i, j)$  is computed as:

$$(13) \quad CritStat(i, j) = \left( \sum_{k=1}^{N_t} Crit_k(i, j) \cdot \alpha^{N_t-k} \right) / \left( \sum_{k=1}^{N_t} \alpha^{N_t-k} \right)$$

where  $N_t$  is the number of different temperatures since the beginning of the simulated annealing process.  $Crit_k(i, j)$  is the value of  $Crit(i, j)$  at the  $k$ th temperature.  $\alpha$  is a decay constant and I use 0.96 in my algorithm. As we can see,  $CritStat(i, j)$  is a weighted mean over all  $Crit(i, j)$  in the history. The weight for the  $k$ th  $Crit(i, j)$  is  $\alpha^{N_t-k}$ . In other words, the criticalities at different temperatures are not treated equally. I assign more weight to a recent criticality value since it is more accurate and reliable. Considering the net-weighting method used in VPR, after constructing the timing graph  $G(V, E)$  at the beginning of every

temperature, VPR uses only  $G$  to compute  $C_T(i, j)$ . My approach considers not only the current  $G$ , but also the previous  $G$ 's in computing  $C'_T(i, j)$ . Utilizing the entire criticality history, I avoid the randomness encountered by general timing-analysis methods and hence increase the accuracy.

The  $History(i, j)$  factor, used in Equation (12), is computed from  $CritStat(i, j)$  as defined in Equation (13). In order to compute  $History(i, j)$ , I divide the simulated annealing process into two phases. As long as the radius to swap two blocks is greater than 1.0, it is in  $Phase_0$ , otherwise it is in  $Phase_1$ .

In  $Phase_0$ , I update  $CritStat(i, j)$  at every temperature, but do not use it to compute  $History(i, j)$  because the statistical data are not enough as guidance. So, in  $Phase_0$ ,  $History(i, j)$  is always 1.0 and does not affect the timing cost.

In  $Phase_1$ , I keep updating  $CritStat(i, j)$  and use it to compute  $History(i, j)$ . Let  $N_C$  denote the number of edges that are considered most timing-critical in history. At the beginning of each temperature, I recompute  $CritStat(i, j)$  for every edge and select  $N_C$  edges with the highest  $CritStat$  values. I call these edges potential critical edges ( $PCE$ ). Also I set the variable  $CritThres$  to the  $(N_C + 1)$ th highest  $CritStat$ . Then I compute  $History(i, j)$  by the following formula:

$$(14) \quad History(i, j) = \max(CritStat(i, j) - CritThres + 1, 1)$$

It can be seen that for the  $N_C$  number of edges with the highest criticalities in the history, their  $History(i, j)$  values are greater than 1. Assume that there are  $N_{edges}$  edges in the timing-analysis graph, then the values of  $History(i, j)$  for all the remaining  $(N_{edges} - N_C)$  number of edges are 1. I only favor the first  $N_C$  edges in the criticality history. And the more critical an edge is in the history, the more it is favored.

In my algorithm,  $N_C$  is an integer constant for a particular circuit. Intuitively, the value of  $N_C$  should be as small as possible. Since only the edges with the potentials to appear in

the post-routing longest path should be favored. On the other hand, it should not be too small, otherwise the probability of missing a final critical edge is high. I use the following formula to compute  $N_C$ :

$$(15) \quad N_C = \max(\sqrt{1.54 \cdot N_{edges}} \cdot (1 - 4 \cdot empty\_rate), 64)$$

where *empty\_rate* is the percentage of unoccupied CLBs on the chip. First,  $N_C$  grows as the total number of edges increases. This is natural because I need to consider more edges as the circuit becomes larger and more complex. Second,  $N_C$  increases as *empty\_rate* decreases. The reason is that when *empty\_rate* is low, the layout is compact and relatively more congested. In this case, favoring a critical edge may easily force other non-critical edges to take detours and become critical. So I need to consider more edges simultaneously. The value of 1.54 and 4 in Equation (15) are obtained through experiments. In addition, I will track at least 64 potential critical edges, so I put a lower bound of 64 in this equation.

Two techniques are used to further improve the performance of my algorithm. First, I observed that my algorithm works better in a less congested environment because it is easier to favor the PCEs without influencing other edges. To do so, I set  $\lambda = 0.3$  in Equation (1) when *empty\_rate* < 2% to alleviate congestion. Otherwise,  $\lambda$  is set to the default value of 0.5. The value of  $\lambda$  for each circuit is shown in Table 5.2. From the above analysis, I shall expect the congestion-driven part of my algorithm to benefit the timing-driven part, because it provides a less congested environment. This explains why my algorithm improves both timing and congestion because these two optimizations favor each other.

The other technique used is to get more criticality data. My algorithm is based on the statistics of criticalities and works better when it gathers more history information. Therefore, I need to modify the annealing schedule. The goal is to keep the total number of moves about the same as in VPR but increase the number of different temperatures. The number of moves evaluated at each temperature is  $(N_{blocks})^{1.33}$  in my algorithm, about 1/10 as in VPR. And the number of different temperature is about 10 times as in VPR. A new



Table 5.1: Temperature Update Schedule

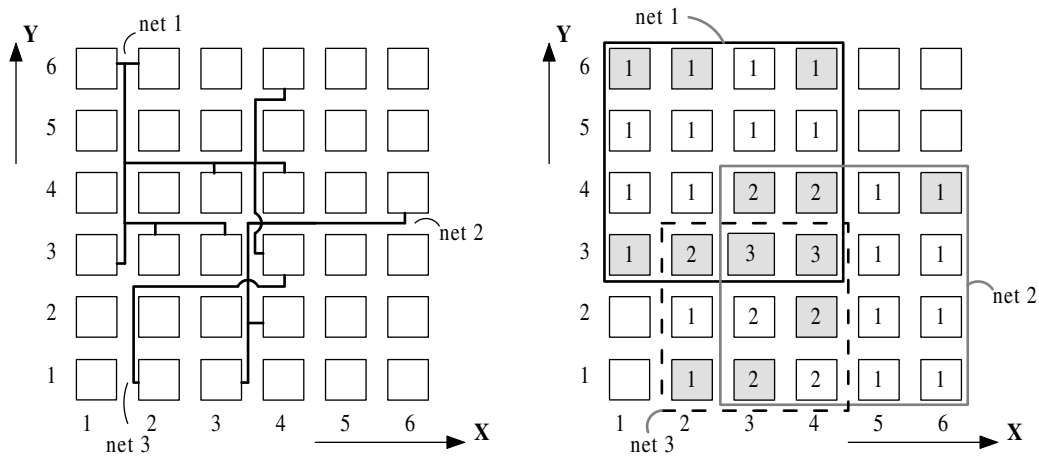
Fraction of moves accepted ( $R_{accept}$ )	$\gamma$
$R_{accept} > 0.96$	0.65
$0.8 < R_{accept} \leq 0.96$	0.976
$0.15 < R_{accept} \leq 0.8$	0.996
$R_{accept} \leq 0.15$	0.93

temperature is computed as  $T_{new} = \gamma T_{old}$ , where  $\gamma$  depends on the fraction of attempted moves that were accepted ( $R_{accept}$ ) at  $T_{old}$ , as shown in Table 5.1.

#### 5.4. Refined Congestion Metric

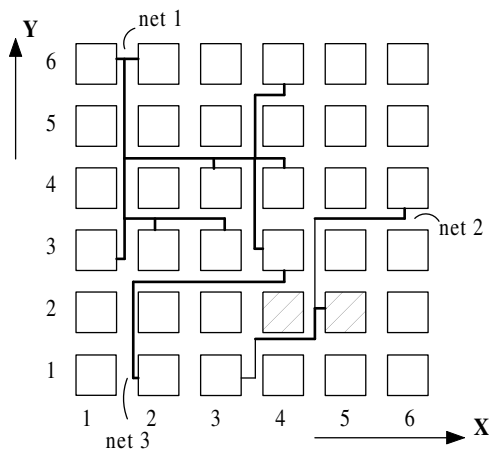
First, let us reexamine my algorithm using Figure 5.4. Figure 4(a) shows a placement for a circuit consisting of three nets. I assume the target FPGA chip consists of 6x6 CLBs. Figure 4(b) shows the corresponding  $U$  array for this placement. The number in each CLB indicates how many bounding boxes are covering this CLB at this moment. A CLB without a label is not covered by any bounding box. For example, the value of  $U_{3,3}$  is 3 since it is inside the bounding box of all the 3 nets, and the value of  $U_{1,1}$  is assigned 0 because it is not inside any bounding box. In Figure 4(b), only the CLBs used by the circuit are shaded. Note that an unused CLB can also be covered by some bounding boxes, like  $CLB_{5,2}$ .

In FPGA based designs, we can hardly utilize all CLBs and hence those unused CLBs are generally neglected and wasted. However, they are valuable since they do not consume any routing resources. Instead, routing tracks around them can be used by other CLBs. So, unused CLBs should be placed in the most congested regions as long as this placement does not degrade other metrics too much. Figure 4(c) is a placement after swapping  $CLB_{4,2}$  and  $CLB_{5,2}$  (striped) in Figure4(a). This swap will probably reduce channel width since the traffic at the center of the chip is reduced. But this swap will not be favored by my algorithm defined in Equation (7) since these two placements have the same  $U$  array as shown in Figure 4(b), and thus the same value of *Congestion*. Similarly, it can not be favored by



(a) Placement with poor routability.

(b) Congestion map.



(c) Placement with good routability.

Figure 5.4: A circuit with three nets: my goal is to achieve (c).

VPR's wiring cost function either, because the dimension and position of all the three nets do not change at all.

My approach addresses this problem by considering unoccupied CLBs and IO pads. The objective is to make the factor *Congestion* smaller when more unoccupied CLBs are placed in congested regions. To quantify the alleviation of congestion brought by an unused block,

I define a factor  $Sat_{x,y}$  indicating the effective percentage of  $U_{x,y}$ . That is, for  $CLB_{x,y}$ ,  $(1 - Sat_{x,y})$  fraction of  $U_{x,y}$  is alleviated. The following formulas show how to compute  $EU_{x,y}$ , the effective percentage of  $U_{x,y}$ ,

$$(16) \quad EU_{x,y} = U_{x,y} \cdot Sat_{x,y}$$

$$(17) \quad Sat_{x,y} = \begin{cases} 1 - N_{un} \cdot allev, & CLB_{x,y} \text{ is used} \\ 1 - N_{un} \cdot allev/2, & \text{otherwise} \end{cases}$$

$$(18) \quad allev = \min(\beta/empty\_rate, 6\%)$$

where  $N_{un}$  is the number of unused CLBs or IO pads adjacent to  $CLB_{x,y}$ . The maximum value of  $N_{un}$  can be 4. I need consider the number of empty blocks adjacent to each CLB. Preferably, I would like to compute  $Sat_{x,y}$  in such a way that the more empty blocks  $CLB_{x,y}$  is adjacent to, the smaller  $Sat_{x,y}$  becomes. This is taken into account by introducing  $N_{un}$  in Equation (17). On the other hand, I want to avoid placing a large number of unused blocks in the same region in order to reduce congestion. This is why I use  $allev/2$  in Equation (17) when  $CLB_{x,y}$  is not occupied. Several facts can be inferred from this set of equations:

- 1) If  $CLB_{x,y}$  is not adjacent to any unused blocks, its  $N_{un}$  is 0 and  $Sat_{x,y}$  is 1, so  $EU_{x,y}$  equals  $U_{x,y}$ .
- 2) If  $CLB_{x,y}$  is adjacent to some unused block(s), its  $EU_{x,y}$  is less than  $U_{x,y}$ .
- 3) When adjacent to the same  $N_{un}$  number of empty blocks,  $U_{x,y}$  of an unused CLB,  $CLB_{x,y}$ , is not alleviated as much as a used CLB.

It is clear that the value of  $allev$  is very important. If it is too small, the effect will be negligible. If it is too large, the locations of empty blocks will become a primary factor when computing the *Congestion* factor in Equation (19). As a result, all empty blocks will be converged to the center of the chip, which is not favorable. Based on my experiments, our algorithm performs well when the  $allev$  factor is smaller than 6%. In general, I want to restrict the value of  $allev$  between 2% to 6%. Since most circuits have an  $empty\_rate$  also

between 2% to 6%, the value of  $\beta$  is set to  $2\% \cdot 6\% = 0.12\%$  in my approach. Also I put an upper bound of 6% to *allev* in Equation (18) in case some circuit has an extremely small *empty\_rate*.

I use the following *modified* congestion function in my approach:

$$(19) \quad Congestion = \left( \frac{\sum_{x,y} EU_{x,y}^2}{nx \cdot ny} / \left( \frac{\sum_{x,y} U_{x,y}}{nx \cdot ny} \right)^2 \right)^k, \quad 1 \leq x \leq nx, 1 \leq y \leq ny$$

Note, I only use  $EU$  in the numerator. When the  $U$  array remains constant, the denominator remains constant. And the numerator will be minimized if unoccupied blocks are moved to the neighborhood of CLBs with highest  $U_{x,y}$  values. So, utilizing the approach above has the effect to move unused CLBs to congested regions.

Based on the discussion above, I can draw two reasonable conclusions.

- (i) If there are plenty of empty blocks, the routability is good by nature. So, I turn off this optimization when *empty\_rate* is greater than 25%.
- (ii) On the other hand, if all empty blocks are IO pads instead of CLBs, this algorithm will not work well since IO pads can only be moved along the borders. According to VPR's layout method, a small value of *empty\_rate* means there are a lot of unused IO pads but very few empty CLBs. So, I turn off this optimization when *empty\_rate* is less than 0.6%.

I also use *empty\_rate* to decide the value of  $k$  in Equation (19). I set  $k$  to 2 for a circuit with a low *empty\_rate* ( $< 4\%$ ) and set to 1 otherwise. The reason is I need to assign more weight to the *Congestion* factor if the circuit is congested by nature.

VPR provides graphic visualization of placement and routing results which helps a researcher understand how well or how poorly an algorithm does. We can get a global view of my placement algorithm by looking at Figure 6.4.2. The details of this figure will be explained in Chapter 6.

Table 5.2: Experiment results: VPR vs. mine.

Circuit			Critical Path Delay			Routing Tracks			Parameters		Statistics		runtime
name	<i>empty_rate</i>	$N_{edges}$	VPR	mine	ratio	VPR	mine	ratio	$k$	$\lambda$	$N_C/N_{edges}$	hit	ratio
s298	0.258%	6951	148.2	136.9	0.924	8	8	1	2	0.3	1.5%	100%	1.76
ex1010	0.562%	16078	174.5	176.0	1.009	12	11	0.917	2	0.3	1.0%	25.0%	1.69
seq	0.794%	6193	109.5	101.6	0.928	12	12	1	2	0.3	1.5%	71.4%	2.11
spla	0.833%	13808	165.6	167.3	1.01	15	16	1.06	2	0.3	1.0%	33.3%	2.41
clma	0.957%	30462	206.5	187.2	0.907	15	13	0.867	2	0.3	0.7%	40.0%	2.41
pdc	1.060%	17193	194.8	206.7	1.061	18	18	1	2	0.3	0.9%	40.0%	2.40
frisc	1.222%	12772	132.5	133.8	1.01	14	13	0.929	2	0.3	1.0%	100%	2.33
diffeq	1.578%	5296	63.72	60.45	0.949	9	8	0.889	2	0.3	1.6%	100%	2.11
s38584.1	1.738%	20840	112.3	82.95	0.739	9	8	0.899	2	0.3	0.8%	100%	2.25
ex5p	2.296%	4002	77.21	79.75	1.033	15	14	0.933	2	0.5	1.8%	0%	2.03
s38417	2.362%	21344	103.3	83.00	0.803	9	9	1	2	0.5	0.8%	63.6%	3.14
apex4	2.623%	4479	103.1	75.43	0.732	14	14	1	2	0.5	1.7%	14.3%	2.56
apex2	2.996%	6692	100.8	94.60	0.939	12	12	1	2	0.5	1.3%	100%	2.76
elliptic	3.144%	12634	136.6	126.0	0.922	13	11	0.846	2	0.5	1.0%	0%	2.84
misex3	3.255%	4968	82.57	88.58	1.073	12	12	1	2	0.5	1.5%	28.6%	2.66
tseng	3.857%	3760	57.96	53.24	0.918	8	7	0.875	2	0.5	1.7%	0%	2.31
alu4	4.875%	5408	90.58	94.76	1.046	11	10	0.909	1	0.5	1.3%	25.0%	3.06
bigkey	41.46%	6313	72.56	55.27	0.762	7	7	1	1	0.5	1.0%	66.7%	1.63
dsip	53.02%	5645	74.37	51.69	0.695	8	7	0.875	1	0.5	1.1%	100%	1.54
des	59.91%	6110	87.21	80.79	0.926	8	8	1	1	0.5	1.0%	0%	1.72
Ave					0.919			0.950			1.2%	50.4%	2.29

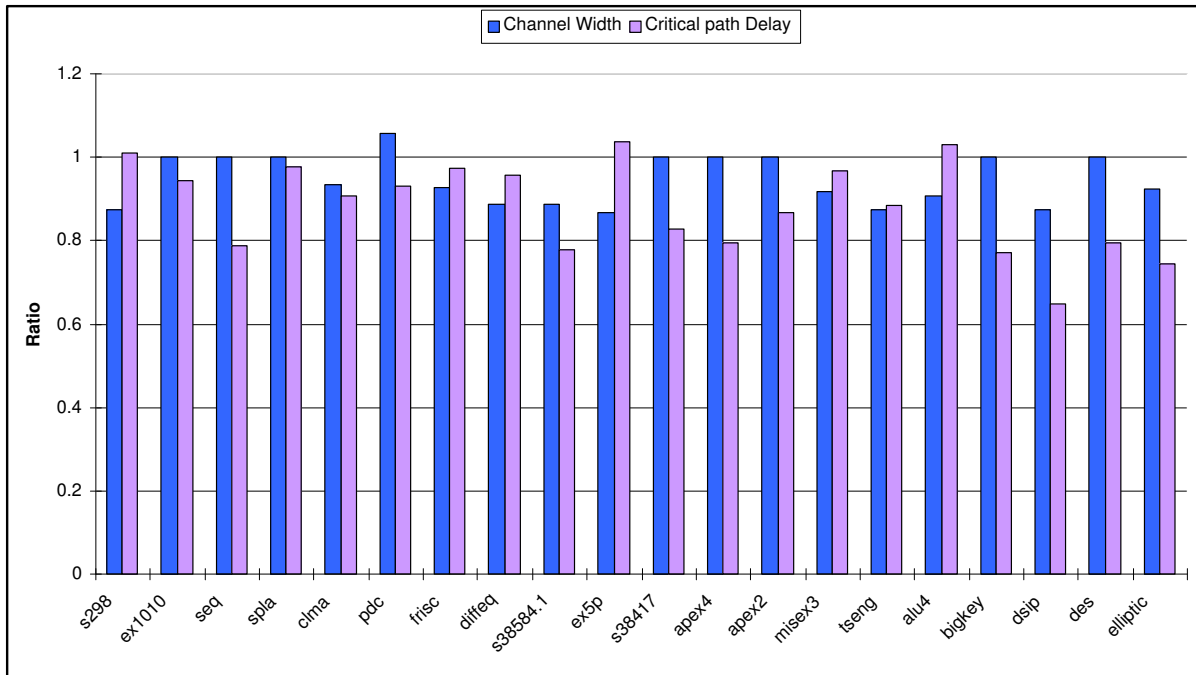


Figure 5.5: Ours (congestion and timing driven) vs. VPR.

## 5.5. Experimental Results

The experimental environment is the same as the one used in Chapter 4. As I made a lot of modifications to VPR, those single-precision floating-point variables cannot provide enough precision any more. So I changed all “float” variables to “double”. To compare with VPR fairly, I also changed all “float” variables in VPR’s source code to “double”. Note, this is the only change that I made to the VPR’s source code.

Table 5.5 shows the experimental results of VPR and my congestion approach. Figure 5.5 gives the corresponding chart. All results are normalized to VPR. Compared with VPR, my algorithm reduces channel width by 5.3% and reduces critical path delay by 11.8%.

## CHAPTER 6

### RUNTIME MINIMIZATION

Recently, as circuit designs become more and more complex, commercial field programmable gate array (FPGA) manufactures keep releasing larger and more powerful FPGA devices. As a direct result, the runtime issue has drawn more attentions than ever before. Runtime is an important metric for a placement algorithm, especially for a simulated annealing based one. This is because although a simulated annealing based approach can generally produce a high quality placement, its runtime is usually prohibitively longer than an *analytical placement* algorithm.

To overcome this drawback, many methods have been proposed. One is to enable simulated annealing only when the temperature is low, like Frontier, a system developed by Tessier to achieve highly routable and high-performance layouts quickly [56]. Another is to utilize hardware to assist simulated annealing, like the systolic structure proposed by Wrighton *et al.* in [60].

In this chapter, I will present three different runtime minimization measures. The first one is proposed by Betz in [5], the second and third are proposed by us.

#### 6.1. Recompute Only the Costs of Affected Nets

The runtime of a placement algorithm is mainly dependent on its computation complexity. However, if I can find a clever incremental computation method, the needed runtime can be reduced significantly. For example, for an algorithm whose complexity is  $O(n)$ , if I can find an incremental method which can be always completed in a constant time, the final complexity will be  $O(1)$ .

The most important runtime optimization techniques comes from the observation that only a small number of nets will be affected in a swap. VPR uses simulated annealing method

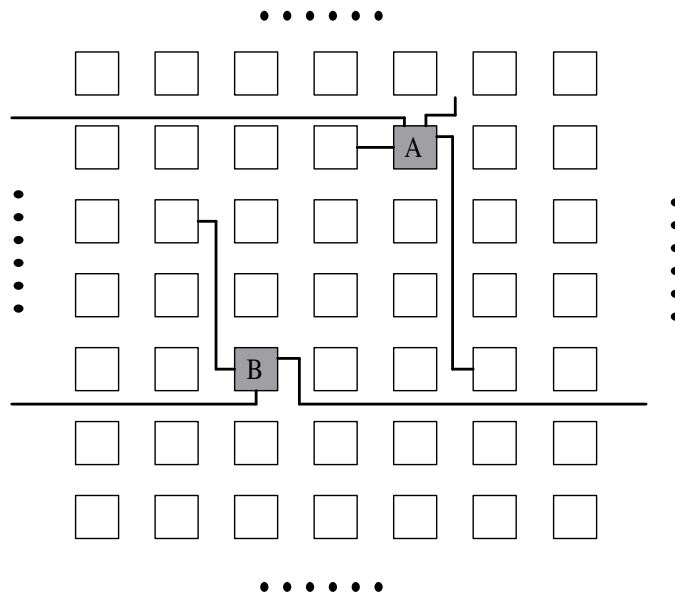


Figure 6.1: Recompute only the costs of affected nets.

to place a circuit. At each step, two random configurable logic blocks (CLBs) are chosen and their locations are swapped. After that I compute the new cost and compare it with the old cost to determine whether to accept this swap or not. The simplest method to compute a new cost is to compute every thing from scratch. But this method is infeasible because there are thousands of nets in a circuit which will make the computation time intolerably long. However, if we take a close look at Equation (2) and Equation (5), it is clear that the timing cost and wiring cost can be decoupled into every net. So in each swap, I only need to recompute the cost for a few affected nets. This is illustrated in Figure 6.1. In Figure 6.1, two CLBs, A and B, are chosen to be swapped. A is connected to 4 nets while B is connected to 3 nets. Although there are much more nets in this circuit, I only need to recompute the new cost for these 7 nets.



## 6.2. Incremental Updating of the $U$ Array

Although the timing-driven part of my algorithm does not cause much runtime overhead, the congestion-driven part actually does. So my main task is to reduce the complexity in computing the *Congestion* factor.

During the process of simulated annealing, each swap causes a set of nets to change their bounding boxes. Every time a net's bounding box is changed, I need to update the  $U$  array. The pseudocode for updating the  $U$  array is shown in Algorithm 6.2.1. The parameter  $n$  is the index of an affected net,  $bb\_old$  and  $bb\_new$  are its bounding boxes before and after the swap. A trivial implementation needs  $bb\_old[n].width \cdot bb\_old[n].height$  number of subtractions and  $bb\_new[n].width \cdot bb\_new[n].height$  number of additions for each affected net. That means, the complexity depends on the area of the bounding boxes. This requires much more computation than VPR's linear congestion method.

To reduce the computation complexity, I can either construct an incremental computation method, enable my optimization only in a fraction of the simulated annealing process, or reduce the area of bounding boxes. These two techniques are both utilized in my algorithm, and are discussed in the following sections.

**Algorithm 6.2.1:** UPDATING THE  $U$  ARRAY( $n$ )

```
procedure UPDATEUSAGEARRAY( $U, n$ )  
  for  $i \leftarrow bb\_old[n].xMin$  to  $bb\_old[n].xMax$   
    for  $j \leftarrow bb\_old[n].yMin$  to  $bb\_old[n].yMax$   
       $U_{i,j} \leftarrow U_{i,j} - 1$   
  for  $i \leftarrow bb\_new[n].xMin$  to  $bb\_new[n].xMax$   
    for  $j \leftarrow bb\_new[n].yMin$  to  $bb\_new[n].yMax$   
       $U_{i,j} \leftarrow U_{i,j} + 1$ 
```

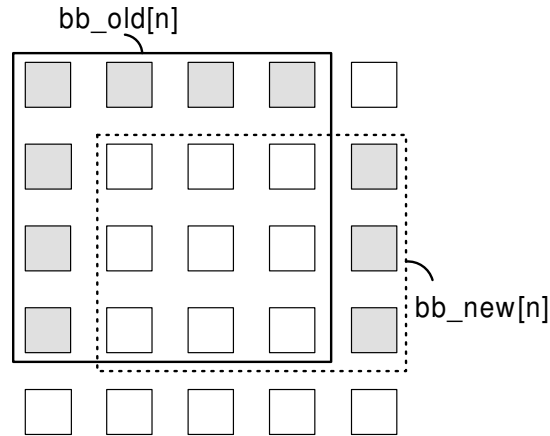


Figure 6.2: Incremental computation of the  $U$  array.

First, not all elements inside the  $bb\_old[n]$  or  $bb\_new[n]$  should be updated. Figure 6.2 shows the bounding boxes of a net before and after a swap. Actually, only the shaded elements need to be updated. The overlapped elements do not change at all. In general,  $bb\_old[n]$  intersects  $bb\_new[n]$ . This is because a net connects at least two blocks and a swap can at most change the positions of two blocks. So I can always use the above optimization to reduce runtime. The overlap region can be computed using the following assignments:

```

overlap.xmin = max(bb_old[n].xmin, bb_new[n].xmin);
overlap.xmax = min(bb_old[n].xmax, bb_new[n].xmax);
overlap.ymin = max(bb_old[n].ymin, bb_new[n].ymin);
overlap.ymax = min(bb_old[n].ymax, bb_new[n].ymax);

```

### 6.3. Trade-off Between Performance and Runtime

Another technique is to enable the congestion optimization only after the swap radius is reduced to 1.0. This technique reduces the runtime considerably in that:

- 1) The length of period when the swap radius equals 1.0 is only about 1/3 of the entire placement period. So about 2/3 computation will be reduced.
- 2) After the swap radius reaches 1.0, the simulated annealing process is about to end. At this moment, the dimension of almost every net (the area of every net's

bounding box) has shrunk a lot. As the complexity of updating the  $U$  array is directly related to the area of a net’s bounding box, this optimization technique is able to reduce computation complexity effectively.

According to my experiments, among the above 2 factors, factor 2 is more important than factor 1. In fact, I think it is factor 2 that makes the runtime ratio between my algorithm and VPR become a constant. That means, the ratio does not grow as the size of the FPGA device grows, which will be analyzed in the following section.

## 6.4. Experimental Results and Analysis

### 6.4.1. Comparison with VPR

The experimental environment is the same as used in Chapter 5. Table 5.2 shows the results of VPR and my algorithm. The circuits are sorted in the ascending order of *empty\_rate*. Compared with VPR, my algorithm reduces the critical path delay by 8.1% and the channel width by 5.0% at the same time. The “ $N_C/N_{edges}$ ” column shows the fraction of edges that are favored in my timing cost computation. Let  $PCE_{last}$  be the set of potential critical edges that are chosen prior to the final temperature in the annealing phase. The “hit” column shows the percentage of the post-routing critical edges that belong to  $PCE_{last}$ . It can be seen that although I only pick up an average of 1.2% edges, the hit rate is above 50%. This explains why my approach reduces the longest path delay so effectively. Another observation is that my algorithm improves timing better when a circuit is less congested. If we only average the timing ratio for those circuits whose *empty\_rate* is over 1.5% (from circuit “diffeq” to “des”), the timing gain is 11.4% which is greater than 8.1%.

The runtime overhead of my algorithm is reasonable, only 2.3X as of VPR’s. What is more important is that the runtime ratio between mine and VPR’s does not increase with the increasing circuit size. Table 6.1 shows that the ratio for the smallest circuit “ex5p” is 2.03, and for the largest circuit “clma” is 2.41. This indicates that my approach has very good scalability. Figure 6.3 compares the runtime ratios when my program is run in two different modes: runtime optimization enabled or disabled. Each point in the figure corresponds to

Table 6.1: Experiment results: VPR vs. mine.

Circuit				Critical Path Delay			Routing Tracks			Parameters			hit	runtime
name	<i>empty_rate</i>	Grid	$N_{edges}$	VPR	mine	ratio	VPR	mine	ratio	$k$	$\lambda$	$N_C/N_{edges}$	ratio	ratio
s298	0.258%	44x44	6951	148.2	136.9	0.924	8	8	1	2	0.3	1.5%	100%	1.76
ex1010	0.562%	68x68	16078	174.5	176.0	1.009	12	11	0.917	2	0.3	1.0%	25.0%	1.69
seq	0.794%	42x42	6193	109.5	101.6	0.928	12	12	1	2	0.3	1.5%	71.4%	2.11
spla	0.833%	61x61	13808	165.6	167.3	1.01	15	16	1.06	2	0.3	1.0%	33.3%	2.41
clma	0.957%	92x92	30462	206.5	187.2	0.907	15	13	0.867	2	0.3	0.7%	40.0%	2.41
pdc	1.060%	68x68	17193	194.8	206.7	1.061	18	18	1	2	0.3	0.9%	40.0%	2.40
frisc	1.222%	60x60	12772	132.5	133.8	1.01	14	13	0.929	2	0.3	1.0%	100%	2.33
diffeq	1.578%	39x39	5296	63.72	60.45	0.949	9	8	0.889	2	0.3	1.6%	100%	2.11
s38584.1	1.738%	81x81	20840	112.3	82.95	0.739	9	8	0.899	2	0.3	0.8%	100%	2.25
ex5p	2.296%	33x33	4002	77.21	79.75	1.033	15	14	0.933	2	0.5	1.8%	0%	2.03
s38417	2.362%	81x81	21344	103.3	83.00	0.803	9	9	1	2	0.5	0.8%	63.6%	3.14
apex4	2.623%	36x36	4479	103.1	75.43	0.732	14	14	1	2	0.5	1.7%	14.3%	2.56
apex2	2.996%	44x44	6692	100.8	94.60	0.939	12	12	1	2	0.5	1.3%	100%	2.76
elliptic	3.144%	61x61	12634	136.6	126.0	0.922	13	11	0.846	2	0.5	1.0%	0%	2.84
misex3	3.255%	38x38	4968	82.57	88.58	1.073	12	12	1	2	0.5	1.5%	28.6%	2.66
tseng	3.857%	33x33	3760	57.96	53.24	0.918	8	7	0.875	2	0.5	1.7%	0%	2.31
alu4	4.875%	40x40	5408	90.58	94.76	1.046	11	10	0.909	1	0.5	1.3%	25.0%	3.06
bigkey	41.46%	54x54	6313	72.56	55.27	0.762	7	7	1	1	0.5	1.0%	66.7%	1.63
dsip	53.02%	54x54	5645	74.37	51.69	0.695	8	7	0.875	1	0.5	1.1%	100%	1.54
des	59.91%	63x63	6110	87.21	80.79	0.926	8	8	1	1	0.5	1.0%	0%	1.72
Ave					0.919			0.950				1.2%	50.4%	2.29

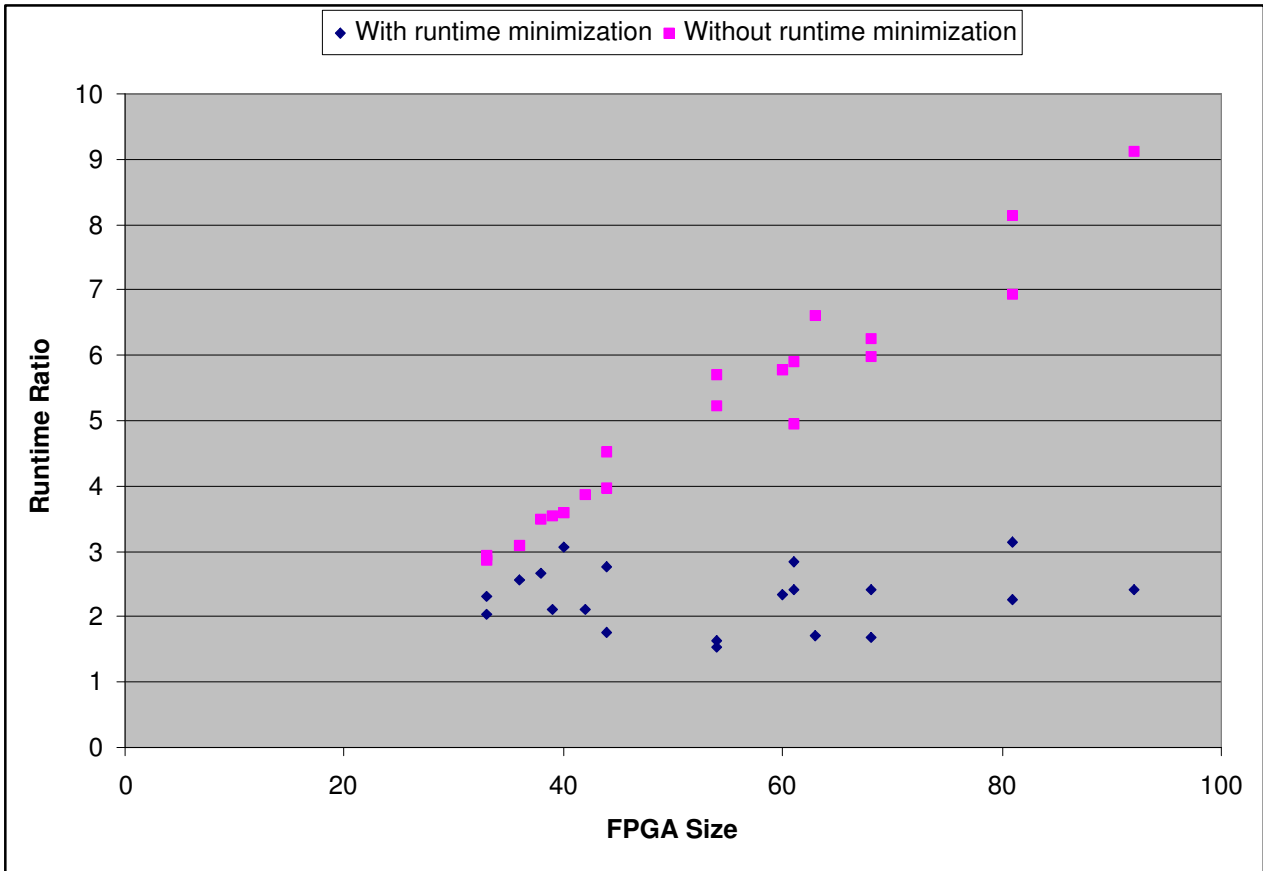


Figure 6.3: The effect of runtime minimization.

a circuit. The x axis is the grid size of the circuit as shown in Table 5.2. The y axis is the runtime ratio relative to VPR when the circuit is placed by my algorithm. A square dot indicates my program runs with runtime optimization disabled. A diamond dot indicates my program runs with runtime optimization enabled. It is clear from this figure that without runtime optimization, the ratio grows up approximately linearly as the size of the device increases. On the other hand, when runtime optimization is enabled, the ratio remains a constant between 1 and 3.

Table 6.2: Comparison of VPR, t-RPack, cMap, SMAC and mine.

algorithm	delay	channel width	runtime
VPR	1	1	1
t-RPack_p	1	0.941	NA
t-RPack_up	0.95	0.973	NA
cMap	0.993	0.93	5.12X
SMAC	0.88	1.22 <sup>a</sup>	100x <sup>b</sup>
<b>mine</b>	<b>0.919</b>	<b>0.950</b>	<b>2.3x</b>

<sup>a</sup>In terms of CLB counts. The post-routing result is not reported.

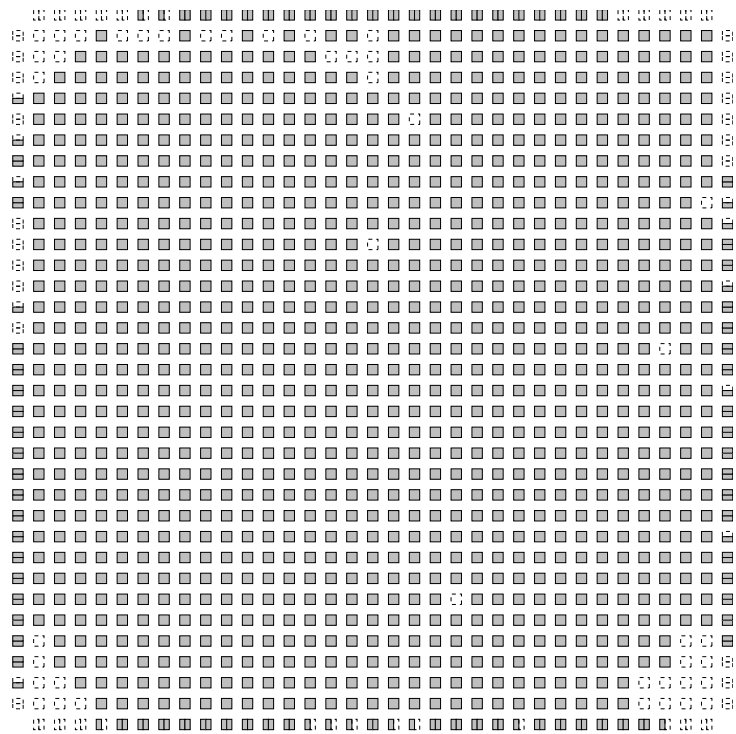
<sup>b</sup>It is compared to DAOmap[8] + T-VPack.

#### 6.4.2. Comparison with Other Research Works

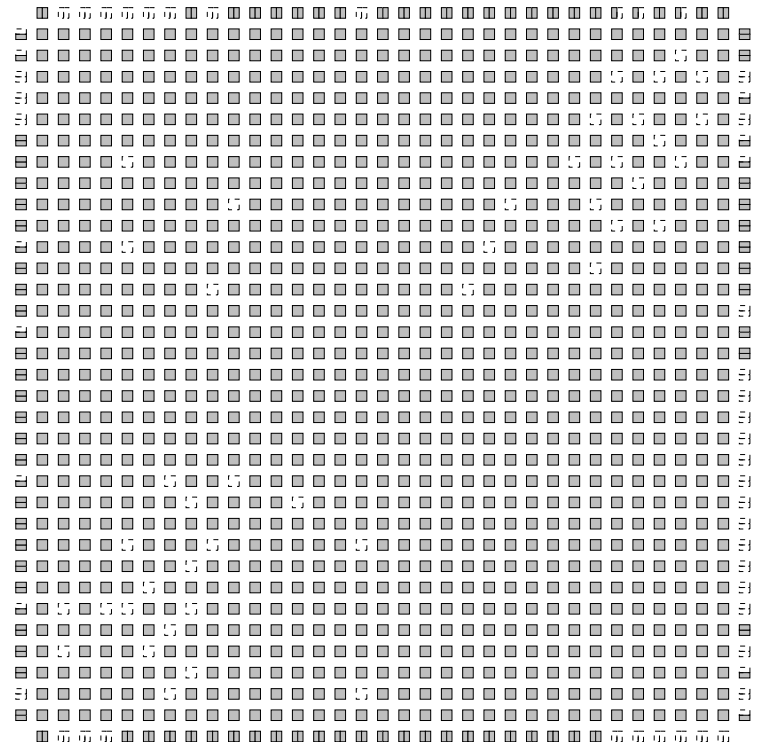
I have also compared my algorithm with many research works published recently. Table 6.2 provides the comparison of several algorithms which are based on VPR. All the metrics are normalized to VPR. There are two rows for t-RPack where t-RPack\_p means it runs in the population mode, while t-RPack\_up means it runs without population. My approach outperforms all of them if we consider timing and channel width together. Also, the runtime of my algorithm is the most efficient among all algorithms whose runtime are available.

As I mentioned, my algorithm moves unoccupied CLBs to the most congested regions. This is justified in Fig.4. Figure 4(a) shows the placement of the circuit “tseng” generated by VPR. The unused blocks are blank and the used ones are shaded. It is clear that almost all unused CLBs are located around the corners as a result of favoring bounding box cost. The placement generated by my algorithm is shown in Figure 4(b). Compared with VPR, we notice the following two facts:

- 1) Along the northeast-directed diagonal, there are a lot of unused CLBs which are dispersed more evenly and attracted to the most congested regions, i.e., the center of the chip.
- 2) empty CLBs are still denser in the corners than at the center of the chip to reduce wirelength. Distributing the empty CLBs this way will alleviate congestion and thus reduce channel width.



(a) The placement of “tseng” by VPR.



(b) The placement of “tseng” by my algorithm.

Figure 6.4: The distribution of unoccupied blocks in the placements of VPR and my approach. I prefer (b) since it is more balanced and is more liable to reduce channel width.



## CHAPTER 7

### CONCLUSIONS AND FUTURE WORK

In this thesis, I presented timing and congestion driven placement algorithms for field programmable gate arrays (FPGAs). My approaches utilize the criticality history to improve timing and disperse unoccupied blocks to alleviate congestion.

My first algorithm is based on congestion map. It reduces reduces channel width by 7.1%, and it does not degrade timing.

My second algorithm considers the history of timing-criticalities. It reduces the average critical path delay by 11.8%, and channel width by 5.3%.

My final approach integrates these two algorithms and minimize the runtime. In summary, It reduces the average critical path delay by 8.1%, and channel width by 5%. Besides, on average it needs only 2.3X runtime as of the Versatile Place and Route (VPR) suite, and the ratio between my algorithm and VPR does not grow with the increasing circuit size.

The placement problem has been studied extensively in the past 30 years. However, recent studies show that existing placement solutions are surprisingly far from optimal. Based on the results from recent optimality and scalability studies of existing placement tools, Cong *et al.* show that the results of leading placement tools from both industry and academia may be up to 50% to 150% away from optimal in total wirelength [11]. If such a gap can be closed, the corresponding performance improvement will be equivalent to several technology-generation advancements. This is why we still need to spend great effort in placement research.

Another issue is to optimize multiple metrics simultaneously in placement because this can enhance the overall performance of a circuit. Usually, we need to trade off among multiple factors, such as timing, channel width, runtime and wirelength. In this work, I found alleviation of congestion may benefit timing as well. In my future research, I would like to further investigate the relationship and trade-off among multiple metrics.

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